

The **FAST** experiment:
A precise measurement of the
muon lifetime τ_μ

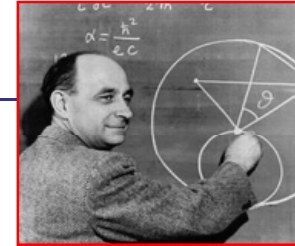
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- Université de Genève -

Université catholique de Louvain, Louvain-la-Neuve
January 10th, 2008

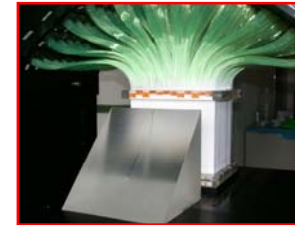
OUTLINE

- **Theoretical motivations & Goal of the experiment**



- **The FAST experiment**

- general experimental concept
- description of the setup elements



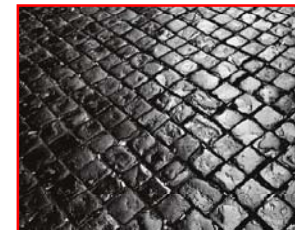
(beam; target; readout; DAQ; LV2 trigger)

- **Muon Lifetime Measurement (2006 data sample)**

- run 2006 data sample
- analysis procedure (from raw data to histograms)
- fit procedure (i.e. muon lifetime measurement)

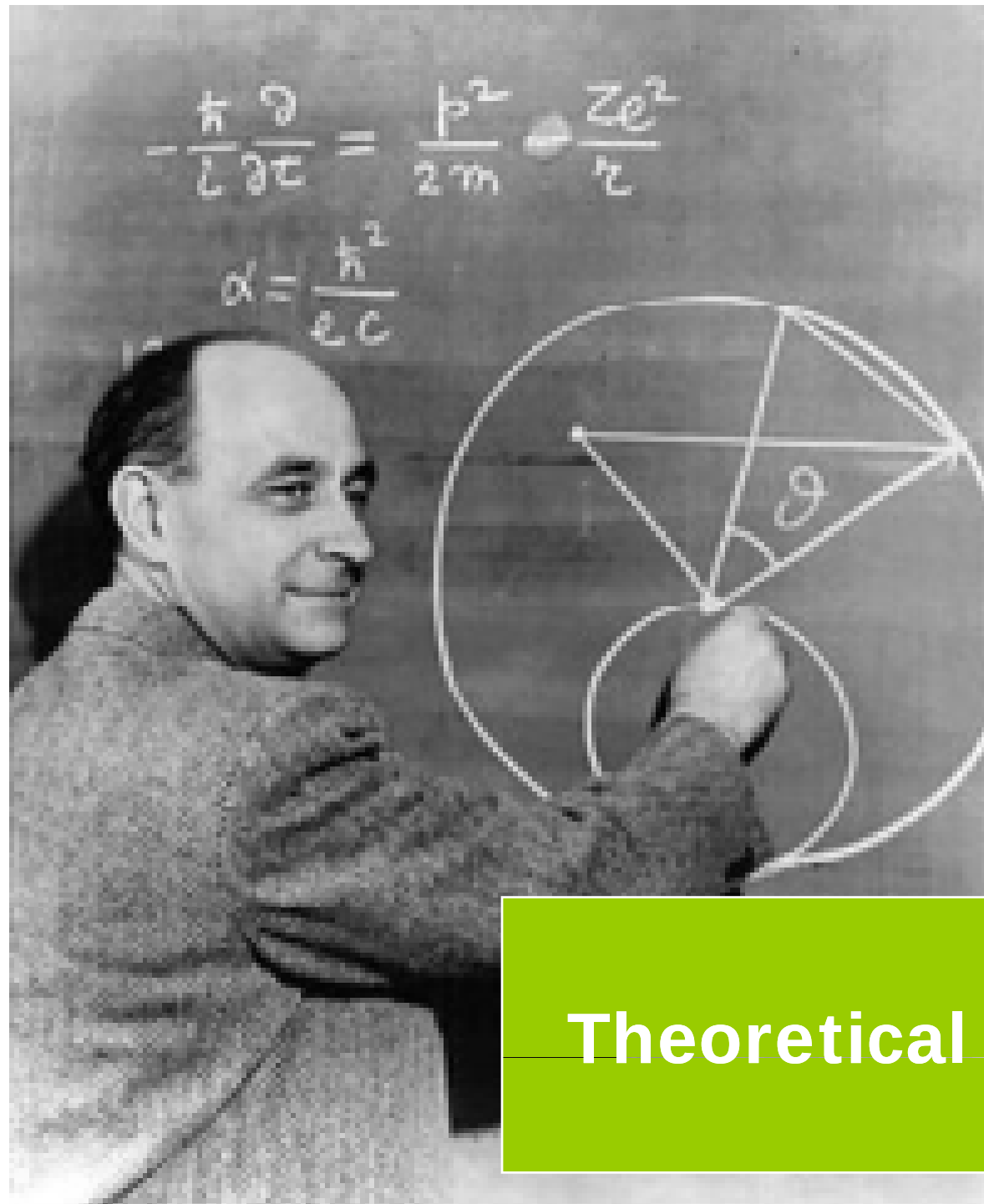


- **Study of the Systematic Uncertainties**



- **Present Status of the Experiment** (2007 beam time)

- **Conclusions**

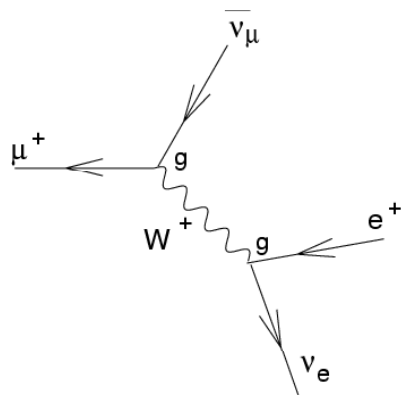
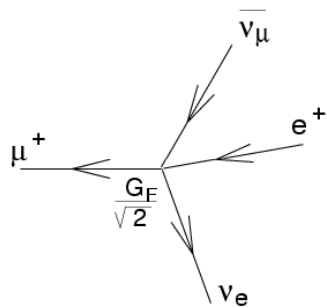


Theoretical Motivations

A PRECISE MEASUREMENT OF τ_μ : WHY ?

$$\tau_\mu \Rightarrow G_F$$

$$\mu^+ \rightarrow e^+ \nu_e \bar{\nu}_\mu$$



- G_F : **one of the input parameter of the SM**
 - SM is predictive only when supplied with a sufficient number of experimental inputs
 - SM of ElectroWeak interaction (BOSONIC SECTOR) : 3 input parameters needed [α , M_Z , G_F]

- G_F : introduced by Fermi in a **contact interaction theory** for the **muon decay** to describe the strenght of a new force (the weak force)

- The muon decay proceeds via **W boson exchange**.
The contact interaction is a valid approximation in the limit of small momenta [$q^2 \ll M_W$]

- G_F is **extracted directly by τ_μ** (in the Fermi model + all orders in α)

$$\tau_\mu^{-1} = \frac{G_F^2 m_\mu^5}{192\pi^3} (1 + \Delta q)$$

electron mass term +
all higher orders QED and QCD
corrections

$$\Delta q = \sum_{i=0}^{\infty} \Delta q^{(i)} \quad \Delta q^{(i)} = \mathcal{O}(\alpha_r^i)$$

[Calculated up to 2nd order]

PDG 2006

$$\tau_\mu = (2197.03 \pm 0.04) \text{ ns}$$

$$\frac{\delta\tau_\mu}{\tau_\mu} = 18 \text{ ppm}$$

PDG 2006

$$G_F = (1.16637 \pm 0.00001) \times 10^{-5} \text{ GeV}^{-2}$$

$$\frac{\delta G_F}{G_F} = 9 \text{ ppm}$$

Louvain-la-Neuve, 10/1/2008

UNCERTAINTY ON G_F

$$\tau_\mu^{-1} = \frac{G_F^2 m_\mu^5}{192\pi^3} (1 + \Delta q)$$

- theoretical uncertainty (i.e. knowledge of Δq)

$$\left. \begin{array}{l} \Delta q^{(0)} \\ \Delta q^{(1)} \\ \Delta q^{(2)} \end{array} \right\} \begin{array}{l} 1970\text{'s} \rightarrow \left(\frac{\delta G_F}{G_F} \right)_{th.} = 15 \text{ ppm} \\ \\ 1999: \textbf{Ritbergen \& Stuart Phys.Rev.Lett. 82, 488 (1999)} \end{array} \quad \begin{array}{l} \text{from predictions of} \\ \text{(uncalculated) } \Delta q^{(2)} \end{array} \quad \left. \left(\frac{\delta G_F}{G_F} \right)_{th.} = 0.3 \text{ ppm} \right\}$$

- experimental uncertainty (i.e. experimental accuracy of the quantities in the τ_μ/G_F formula)

$$\left(\frac{\delta G_F}{G_F} \right)_{exp} = -\frac{1}{2} \frac{\delta \tau_\mu}{\tau_\mu} - \frac{5}{2} \frac{\delta m_\mu}{m_\mu} + \left(4 \frac{m_{\nu_\mu}^2}{m_\mu^2} \right)$$

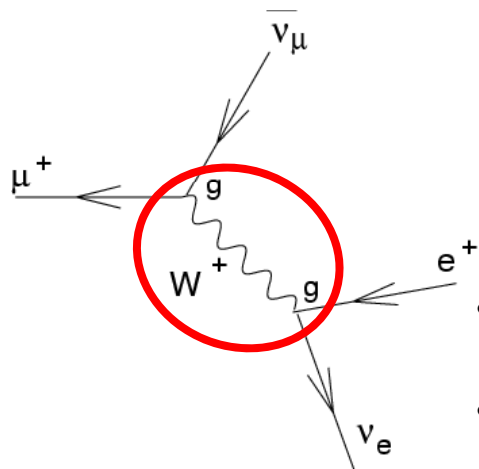
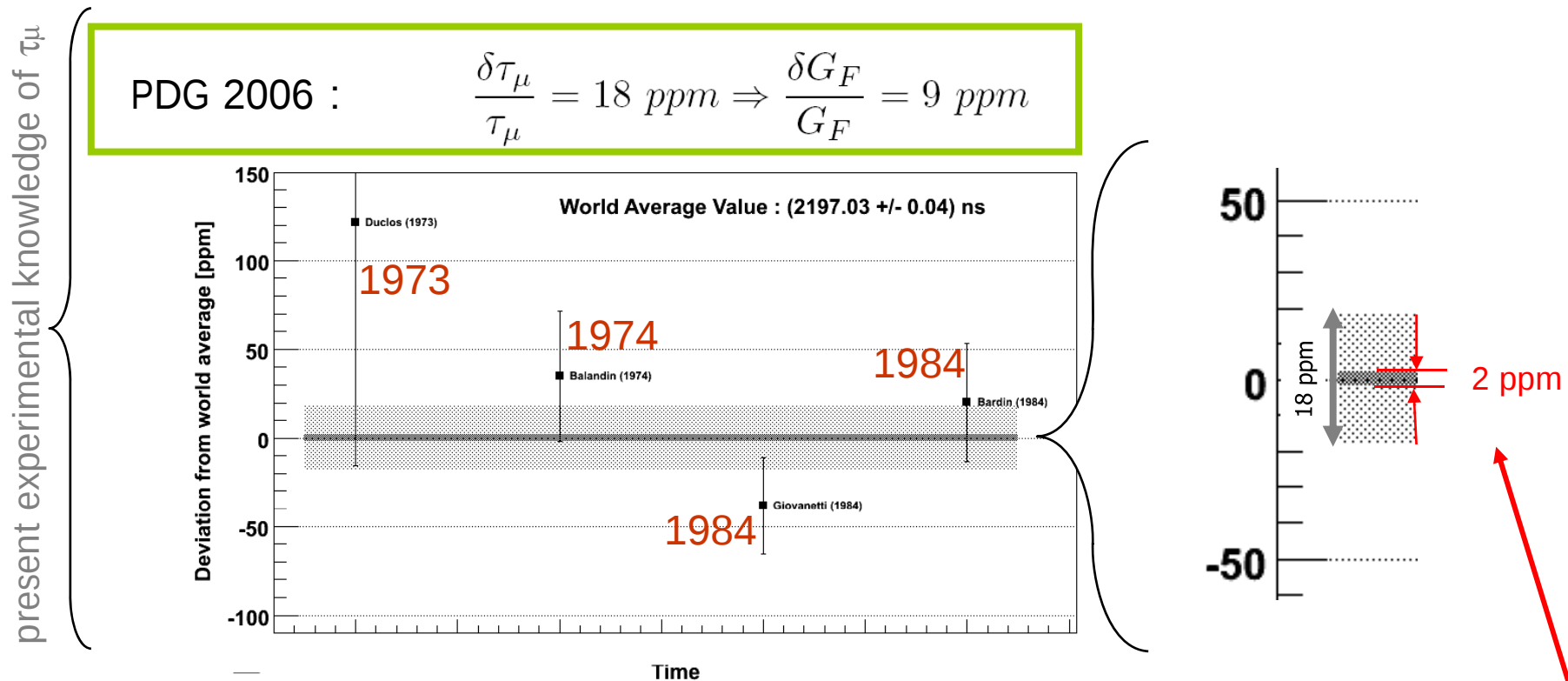
9 ppm 0.2 ppm < 13 ppm (direct meas.)
0 (CMB & neutrino oscill.)

$$\left. \left(\frac{\delta G_F}{G_F} \right)_{exp} = 9 \text{ ppm} \right\}$$

	relative precision	contribution to $\delta G_F/G_F$	
τ_μ	18 ppm	9 ppm	
m_μ	0.09 ppm	0.2 ppm	
m_{ν_μ}	-	< 13 ppm	$m_{\nu_\mu} < 0.19 \text{ MeV (90\% C.L.)}$
	-	0	$< 2 - 3 \text{ eV (95\% C.L.)}$

At present, the (exp) accuracy on τ_μ is the limiting factor for an improved precision on the Fermi Constant G_F

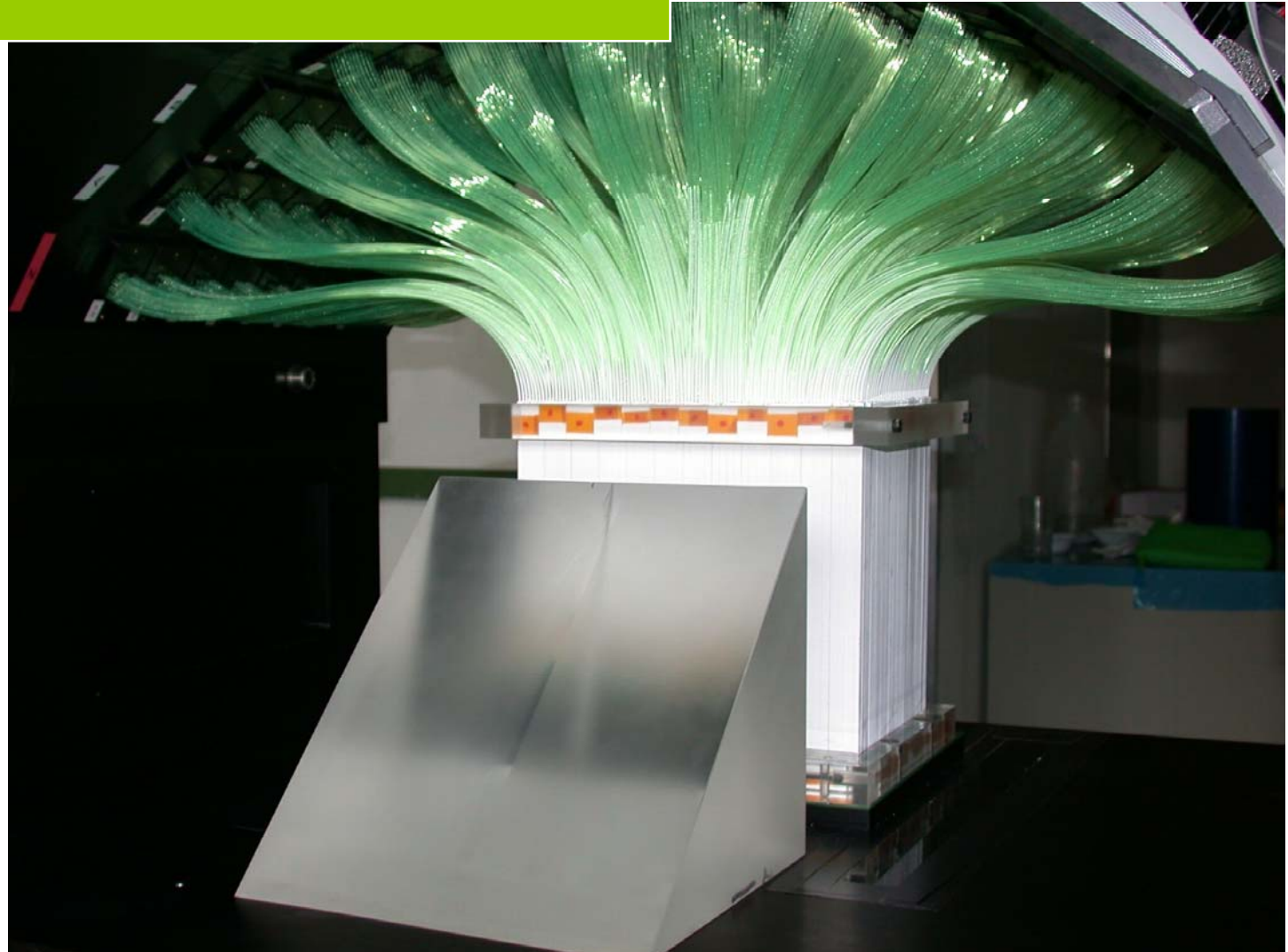
Experimental knowledge of τ_μ & GOAL of the FAST EXPERIMENT



FAST GOAL : $\frac{\delta\tau_\mu}{\tau_\mu} = 2 \text{ ppm} \Rightarrow \frac{\delta G_F}{G_F} = 1 \text{ ppm}$

- precise enough to show the effects of the W propagator in G_F calculation
- **FAST: high energy experiment performed at a low energy scale**

The FAST Experiment



THE FAST COLLABORATION

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CERN ¹

CIEMAT ²
Ciemat



UNIGE ³

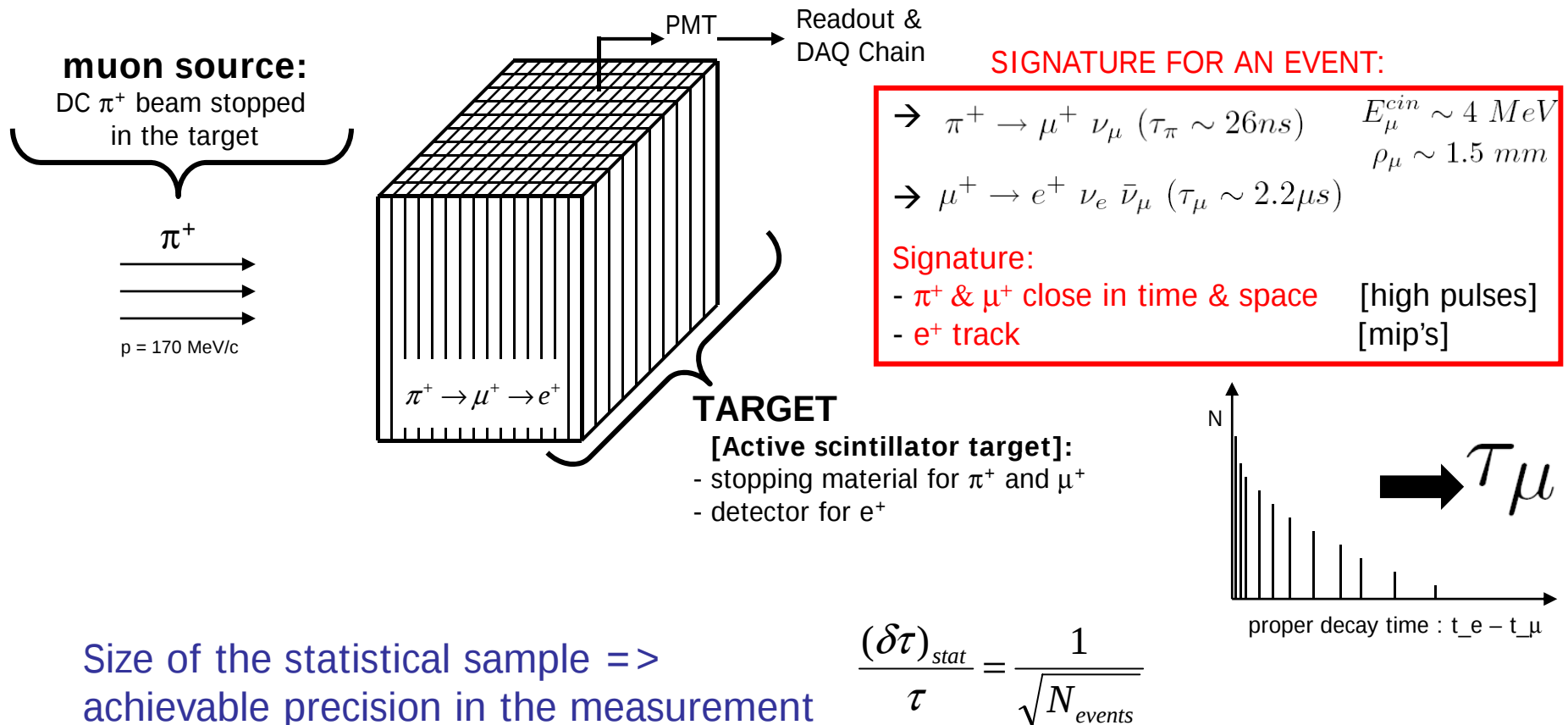
UNIVERSITÉ DE GENÈVE

PSI ⁴

PAUL SCHERRER INSTITUT
PSI



DESIGN of the FAST EXPERIMENT



New generation muon lifetime experiments ($\delta\tau_\mu/\tau_\mu \sim ppm$) → 2 main requirements:

1. Achieve a large statistical sample ($N_{events} \sim 10^{11} - 10^{12}$)
2. Control the systematic effects

DESIGN of the FAST EXPERIMENT

1. Large statistical sample:

$$\left. \begin{array}{l} \frac{\delta\tau_\mu}{\tau_\mu} \sim 2 \text{ ppm} \Rightarrow N_{\text{evts}} \geq 2.5 \times 10^{11} \\ \text{observation period per event: } 10 \tau_\mu \rightarrow 20 \mu\text{s} \end{array} \right\} 10^{11} \times 20 \mu\text{s} / \text{eff}(0.5) \sim O(\text{year}) \quad \text{Only for data taking}$$



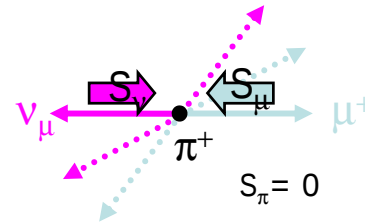
2. Suppress systematic effects:

- | | |
|----------------------------|--|
| pile-up effects | • high granularity, imaging detector, uniform occupancy |
| Gain shifts / event losses | • DC beam |
| μ SR effects | <ul style="list-style-type: none">• unpolarized & isotropic muon source (from π decay at rest)• range cuts for beam muon suppression• large angular acceptance and isotropic detection efficiency• local magnetic field to assess residual systematics |

MUON SOURCE (i.e. DC π^+ BEAM)

μ source = π decay at rest in the target

→ isotropic & unpolarized μ source

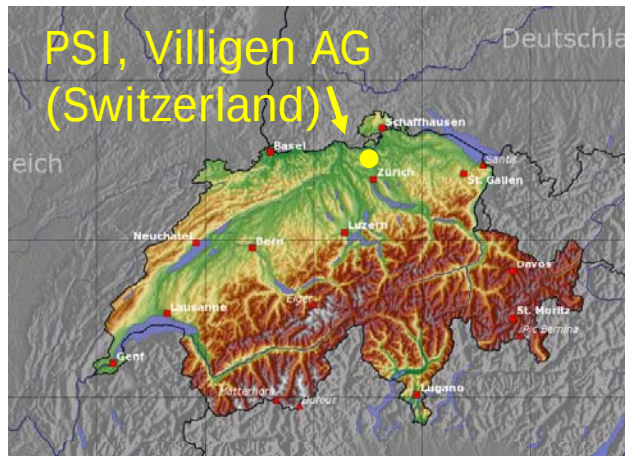


DC π^+ BEAM @ Paul Scherrer Institute (PSI)

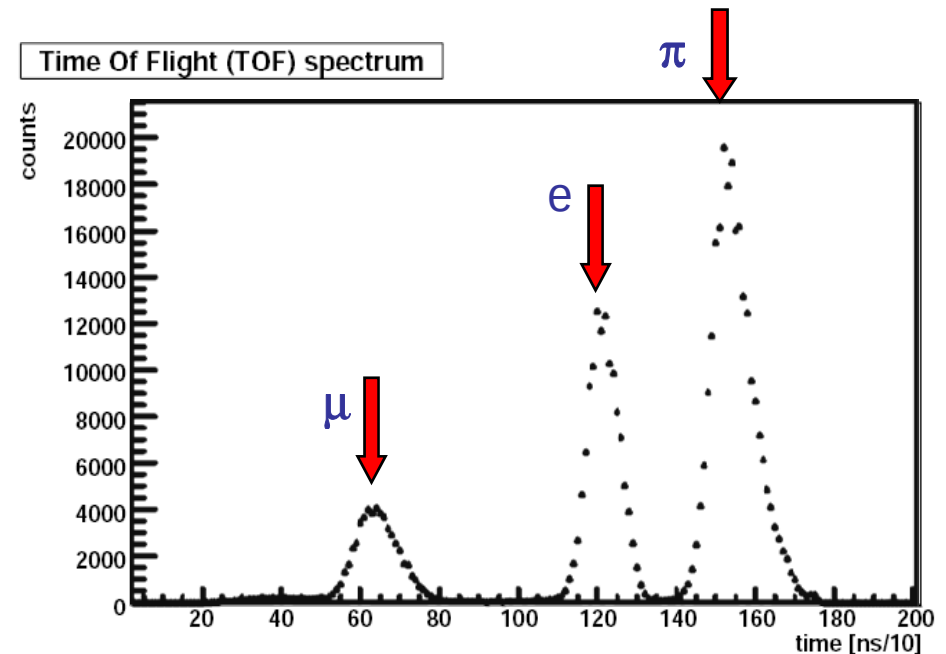
PSI :

proton
cyclotron
(590 MeV)
(2mA p curr)

several
secondary
beamlines

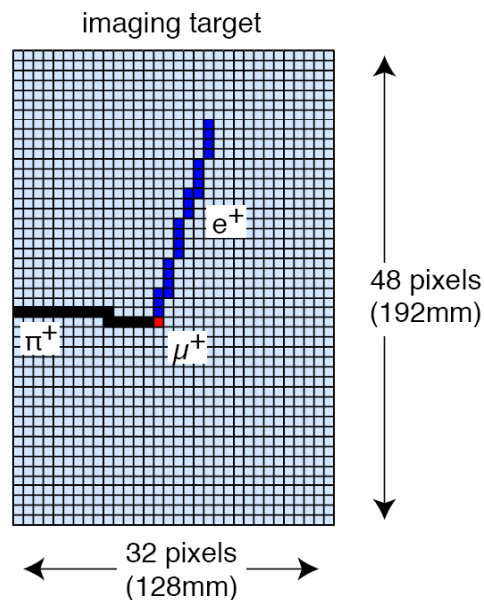


- π M1 area : π^+ DC beam
- momentum : **170 MeV/c** ($\pm 3\%$)
- RF frequency : 50.633 MHz (T=19.75 ns)
- size : variable (**$\sim 10 \times 10 \text{ cm}^2$**)
- intensity : variable (**$\sim 500 \text{ kHz}$**)
- purity : $\sim 50\%$



TARGET

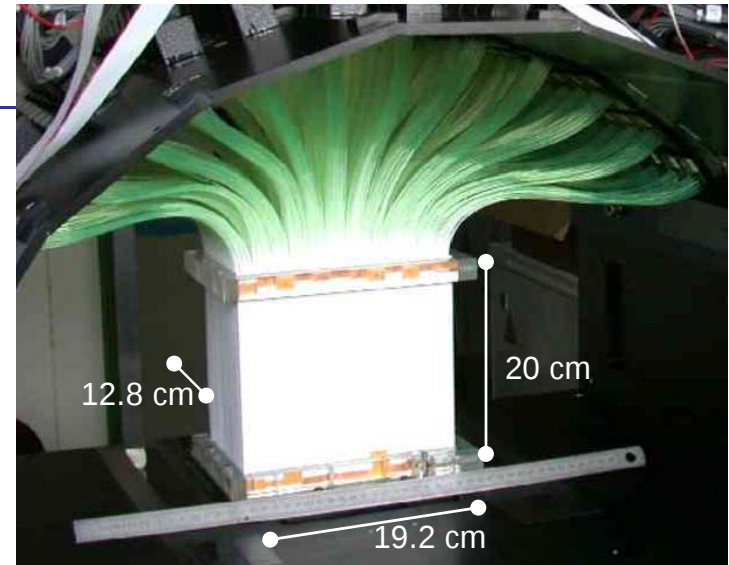
- Active target :
 - stopping material for π^+/μ^+
 - detector for the particles
- Solid plastic scintillator (Bicron BC400)



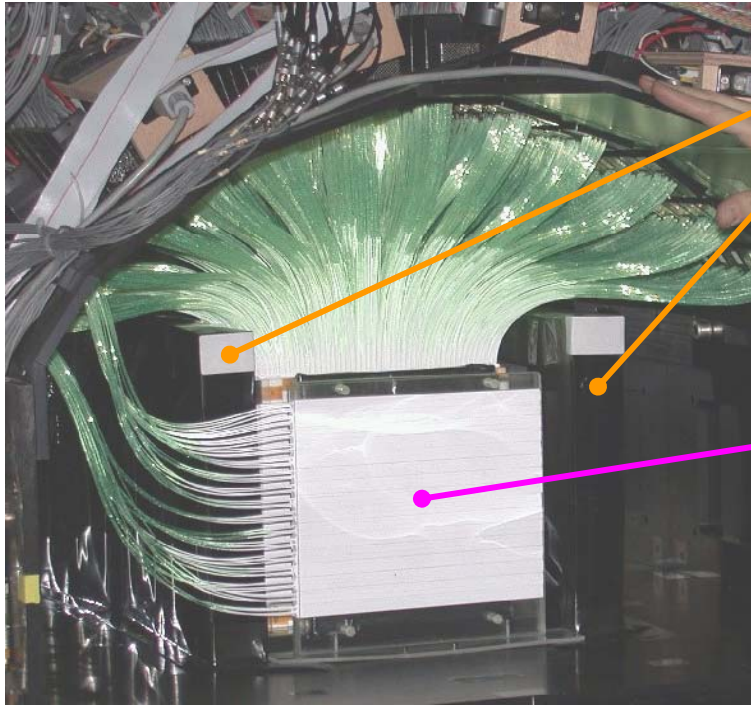
- requirements imposed by the design:

- high granularity
- tracking capabilities
- fast imaging detector
- identical replicated **mini-detectors**
- vertical arrangement 32 x 48

- **1536 pixels** (8 x 12 [4x4]-bundles)
- 1 pixel = scintillator bar (4 x 4 x 200 mm³) with 2 WLSF



TARGET: FINAL CONFIGURATION

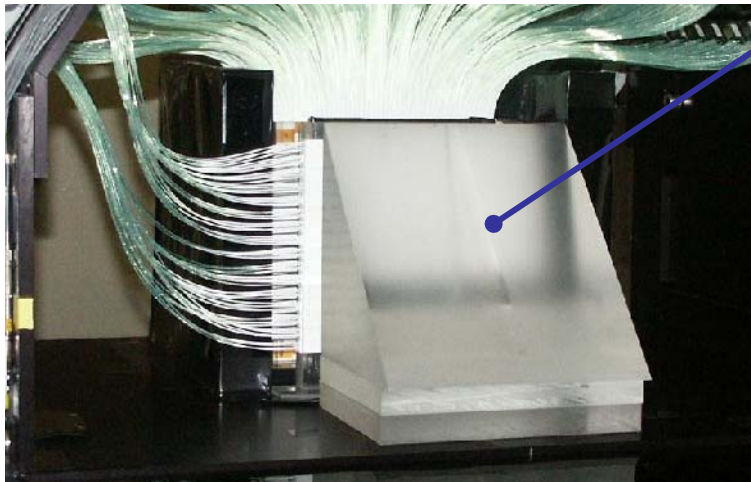


dipolar magnetic field:

- permanent magnet
(2 planes of magnetized ferrite blocks)
- $B = 80 \text{ G}$
- homogeneous & transverse magnetic field
- assess systematics related to μSR effects

z-counter hodoscope:

- 16 horizontal counters (10x10x200mm³)
- register vertical entry position of the beam pions
- range requirements on beam pions



wedge shaped beam degrader

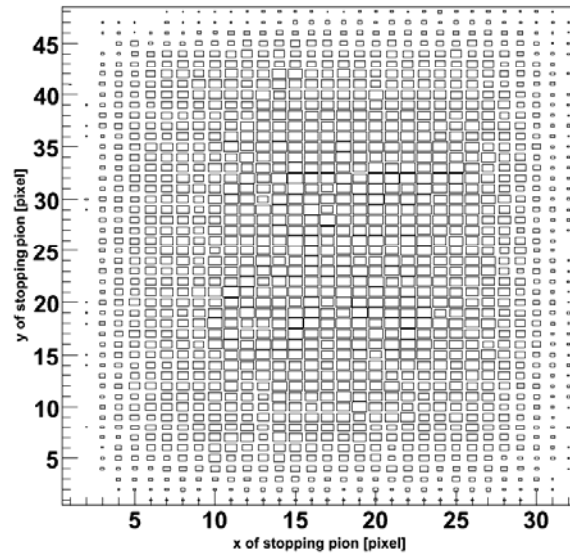
- vertical gradient in the thickness of the absorber
- achieve a uniform distribution of the stopping pions points
(combined with large beam profiles)

TARGET: OCCUPANCY & RANGE REQUIREMENTS

achieved **uniform occupancy** of pion stopping point

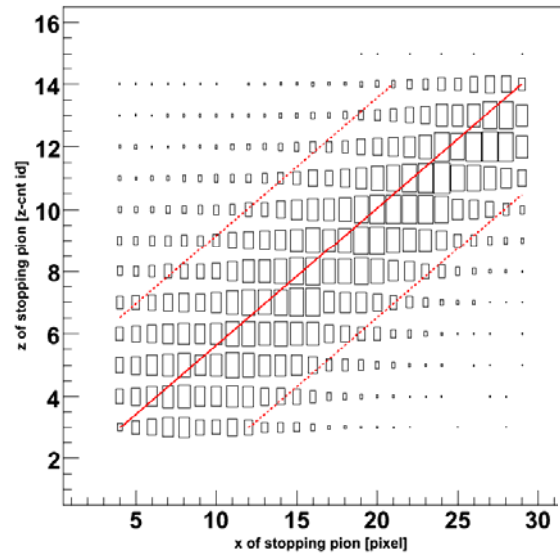
PION BEAM (nominal running conditions)

Stopping Pion Distribution: (x,y) plane

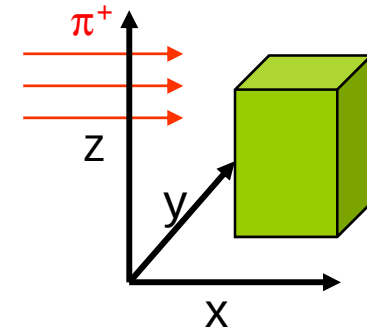


transverse plane (x,y)

Stopping Pion Distribution: (x,z) plane



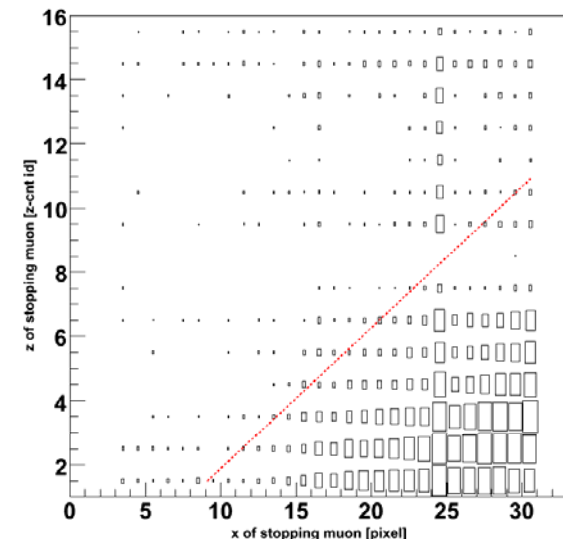
vertical plane (x,z)



MUON BEAM

vertical plane (x,z)

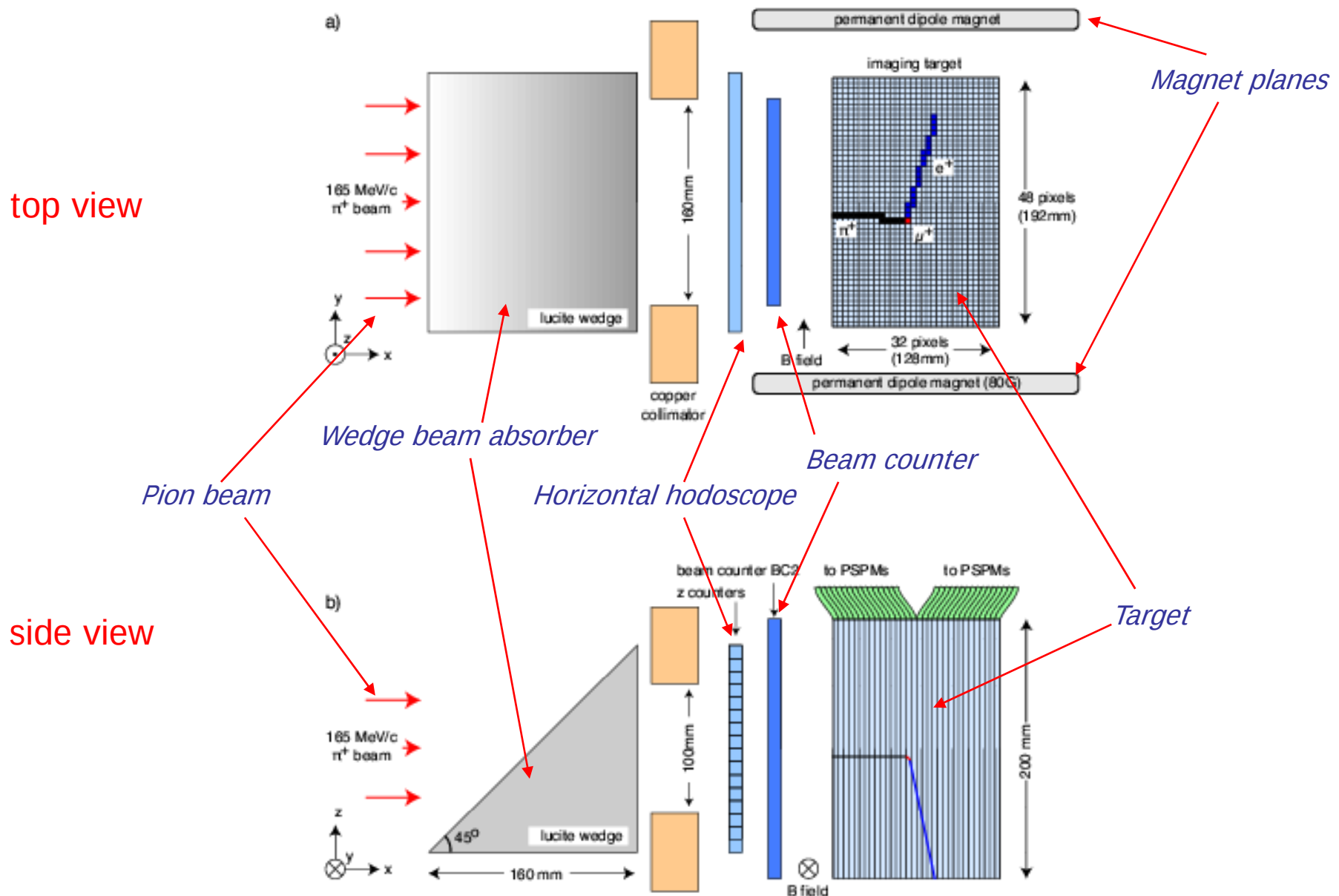
Stopping Muon Distribution: (x,z) plane



Strong range separation (20 pixel ~ 8 cm)
between beam π 's and μ 's :

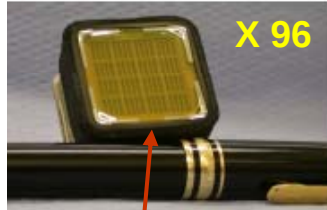
Wedge + hodoscope z-cnt tags
efficient suppression of residual beam muons

FAST: GLOBAL SETUP OVERVIEW



FAST: READOUT & DAQ CHAIN

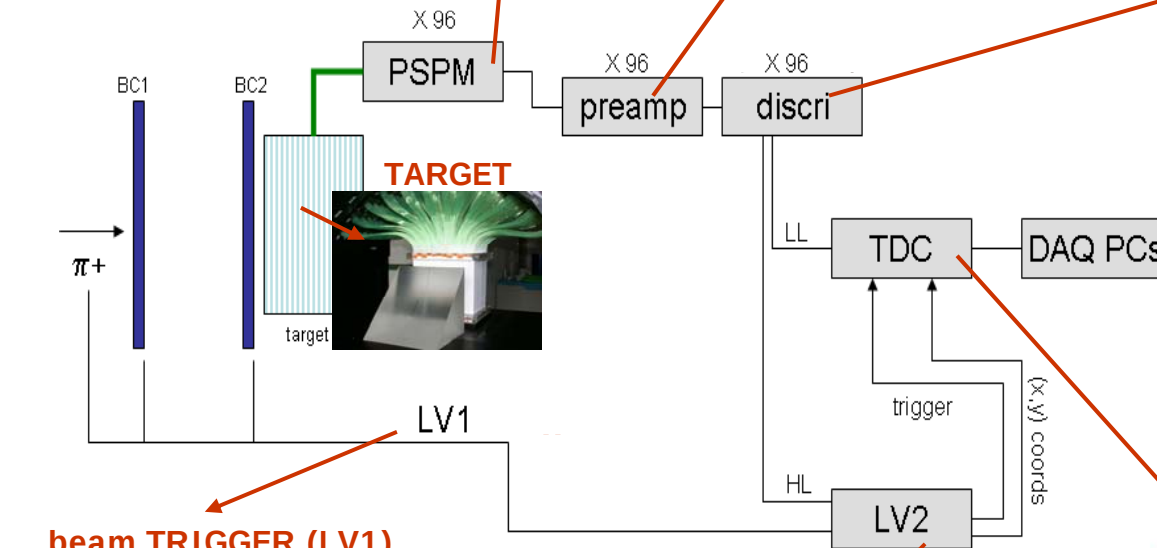
- Position Sensitive **PhotoMultipliers (PSPM's)**
- Hamamatsu H6568-10
- multianode (4x4)



- **Preamplifiers**
- shaper & preamp (x5)
- custom made units (PSI)

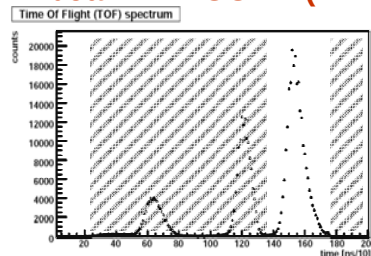


- **Double THR discriminators**
- LOW (LL) & HIGH (HL)
- LL $\rightarrow$ mip's (e^+ tracks)
- HL $\rightarrow \pi^+ / \mu^+$ (stop points)
- remotely adjustable thr (50 mV – 2 V)
- custom made units (PSI)



Particle Type	Light Yield [pe]
electrons (i.e. mip's)	9
pions with 20 mm range	25
stopping pions	35
$\pi \rightarrow \mu$ decay	35
LL $V_{thr} = 100$ mV	~ 3
HL $V_{thr} = 400$ mV	~ 18

beam TRIGGER (LV1)



- Narrow BC1.BC2.RF coinc
- Selective trigger on pions

Second Level TRIGGER (LV2)

- Hardware trigger for the TDCs
- **DATA REDUCTION SYSTEM**
- Custom made FPGA based electronics (CIEMAT)



- **CAEN v767 128-channels TDCs**
- time stamping of the raw pulses from discri
- output to the DAQ chain

TIME MEASUREMENT: TDCs & DAQ

TDC task → time stamping of the raw pulses (LL disci outputs)



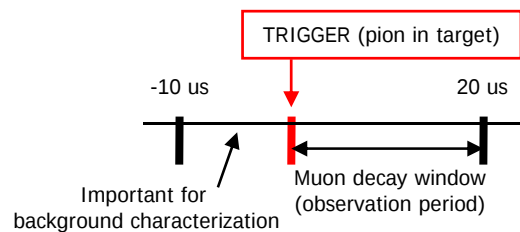
- precise time measurement
- high rate capabilities



- CAEN v767 128-channels TDC's [x 16]
- External Rb clock [30 MHz]: stability : $\Delta t/t \sim 10^{-10}$
- 1 TDC tickmark = 1.041667 ns [1 TDC tick = 1 clock period/32 bits]
- for every hit in the target : (x,y,time)

16 TDC units needed
to read out the target
2048 channels
(1536 data hits +
control words)

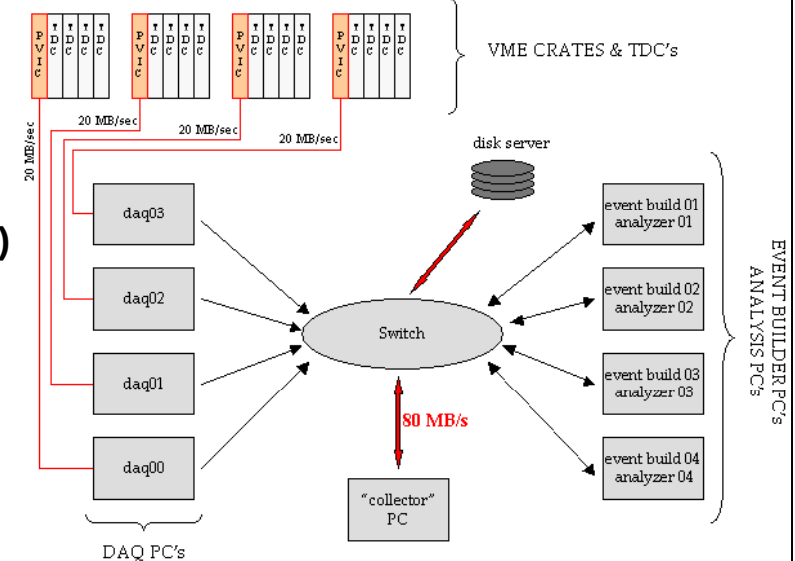
- internal circular buffer:
[-10,+20] μ s w.r.t trigger
trigger = π in target



DAQ ARCHITECTURE

- 16 TDC's accommodated in 4 VME crates
- VME-PCI interface: PVIC link (20 MB/s/node)

80 MB/s : MAX ALLOWED BANDWIDTH



DATA THROUGHPUT & BANDWIDTH

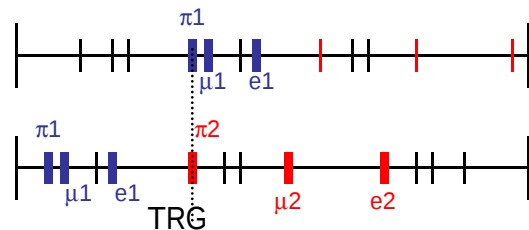
20 MB/sec per DAQ PVIC node; 4 nodes

(Dec 2007: upgrade to 8 nodes)



max achievable bandwidth: **80 MB/sec**
(160 MB/sec)

- parallelisation → high beam rate
- high granularity → 1536 data channels + control words
- 30 usec time window



events repeated several times
if overlapping triggers



huge event size
huge data bandwidth

from simulations: full target read for each event →

bandwidth ~ **2000 MB/sec**

➡ NEED of a DATA REDUCTION SYSTEM

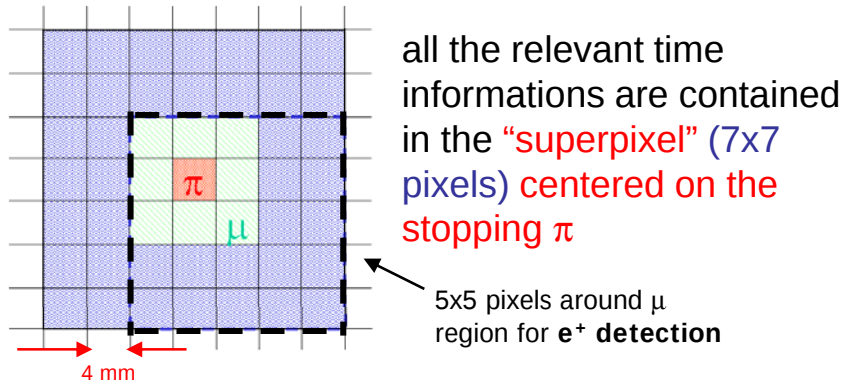
➡ LV2 TRIGGER SYSTEM :

- Hardware trigger to the TDCs
- Selective trigger for the TDCs
- Event data quality selection

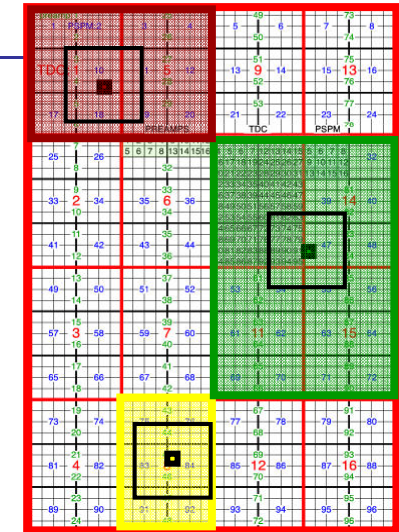
➡ Reduce the data throughput at an early stage for the DAQ

2nd LEVEL TRIGGER (LV2)

LV2 trigger idea / SUPERPIXEL logic:



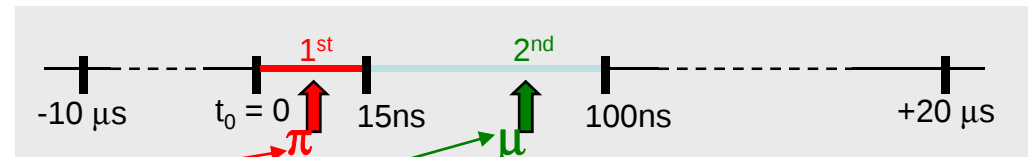
- no need to read out the full target for every event
- **RoI** : only 1, 2, or 4 TDCs (depending on the pion position)



[LV2 input : HL discri output]

LV2 operations :

- Look for pion stop point (1st snapshot)
- Look for muon decay (2nd snapshot)
- Decide which TDCs should be triggered (RoI, i.e. TDCs containing superpixel)
- Send the trigger to the TDCs
- Send muon coordinates as additional information



LV2 as DATA REDUCTION SYSTEM :

1. Selective trigger (RoI)
2. Event selection tool (only evts with π stop & $\pi \rightarrow \mu$ decay retained)



Analysis (2006 data sample)

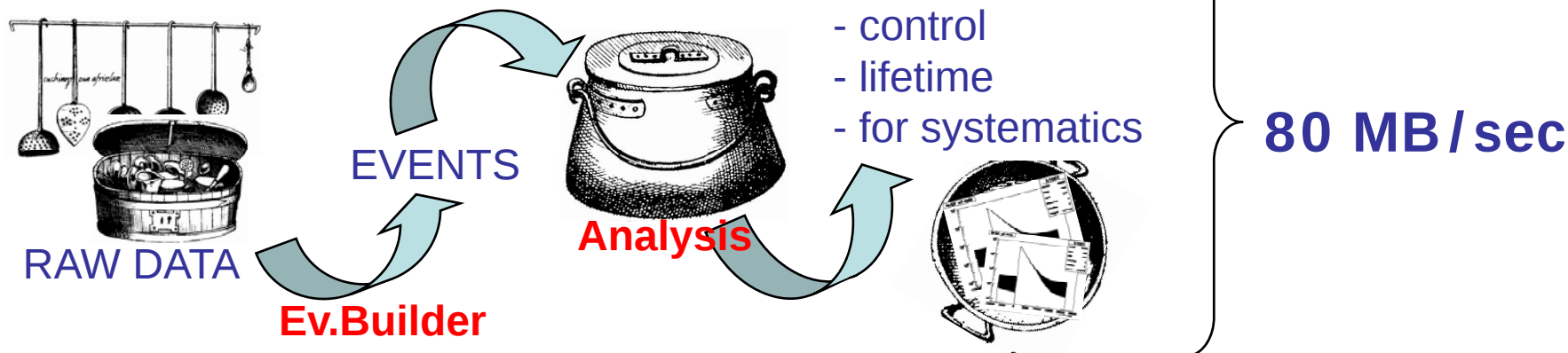
RUN 2006: DATA SAMPLE

- **3 weeks data taking** (Nov – Dec 2006)
- first physics data taking run for FAST
- running conditions very close to the final ones
except for the reduced adopted rate :
LV2 trigger rate ~ 30 kHz (pion rate ~ 80 kHz)

- **total statistics :**
 1.073×10^{10} events
→ precision comparable
with world average

Run 2006: Data Samples		
Sample ID	Sample Name	N. events
1	01a	$2.068 \cdot 10^9$
2	01b	$1.070 \cdot 10^9$
3	02	$0.266 \cdot 10^9$
4	03	$0.886 \cdot 10^9$
5	04	$0.974 \cdot 10^9$
6	05	$0.562 \cdot 10^9$
7	06	$2.022 \cdot 10^9$
8	07	$1.565 \cdot 10^9$
9	08a	$0.928 \cdot 10^9$
10	08b	$0.390 \cdot 10^9$
Full Statistics (Run 2006)		$1.073 \cdot 10^{10}$

ANALYSIS TASKS



- Main role of the analysis:

1. in every event recognize the correct $\pi \rightarrow \mu \rightarrow e$ chain

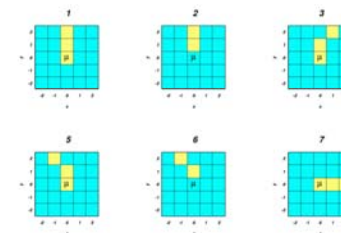
- Pion ID
 - Muon ID
 - Positron ID
- From LV2 hardware

2. measure the time of the particles

3. fill the histograms



- 512 predefined pattern topologies



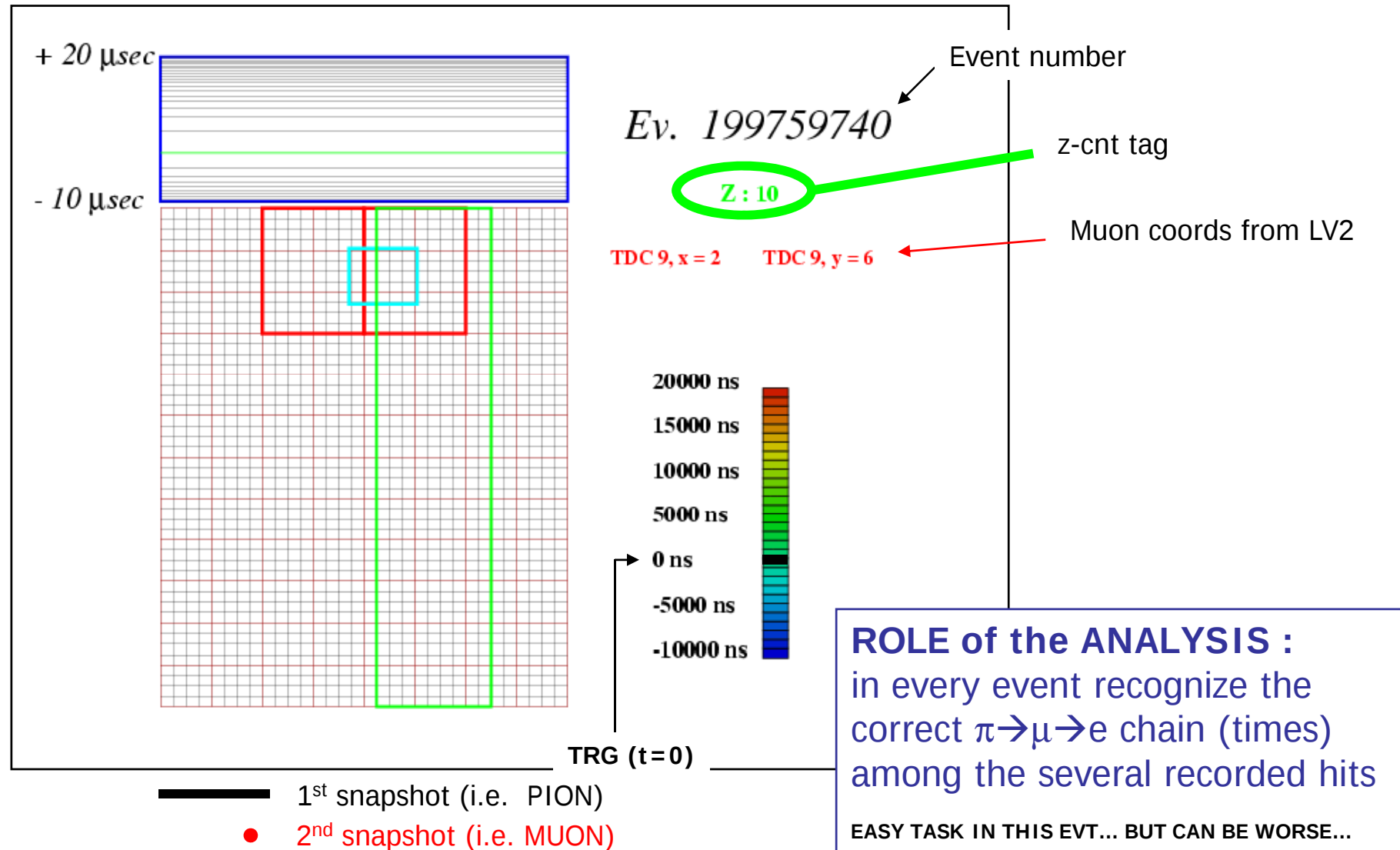
- any time in the TDC window is allowed
- electron time = average track time
- only 1 positron candidate allowed

- **ONLINE ANALYSIS :**

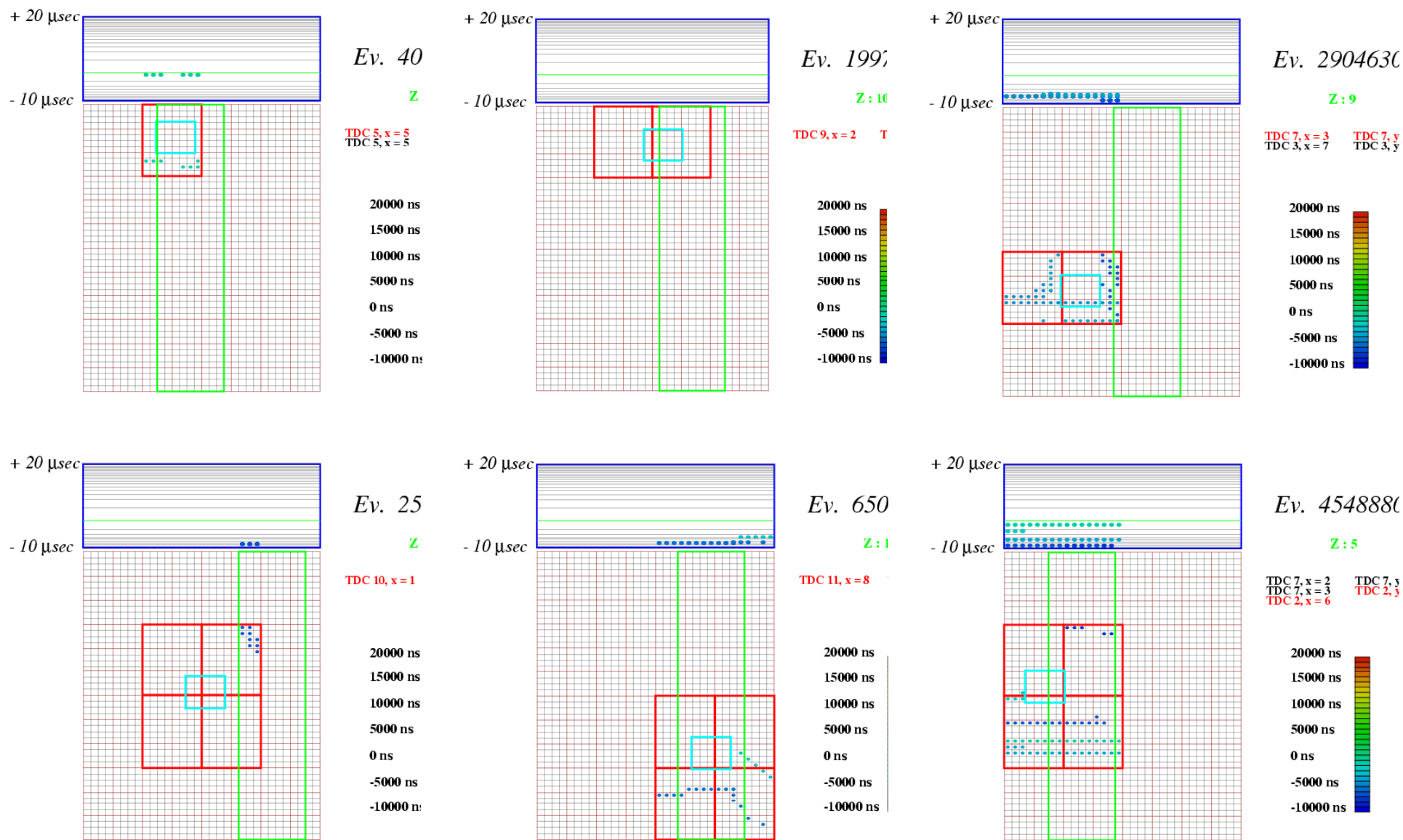
- 80 MB/sec ~ **7 TB/day**
- Impossible (& unpractical) to store data
- **Only histograms are** (periodically) **saved** (together with a prescaled fraction of data)
- **ORIGINAL BULK OF RAW DATA IS LOST !!!!**

EVENT DISPLAY

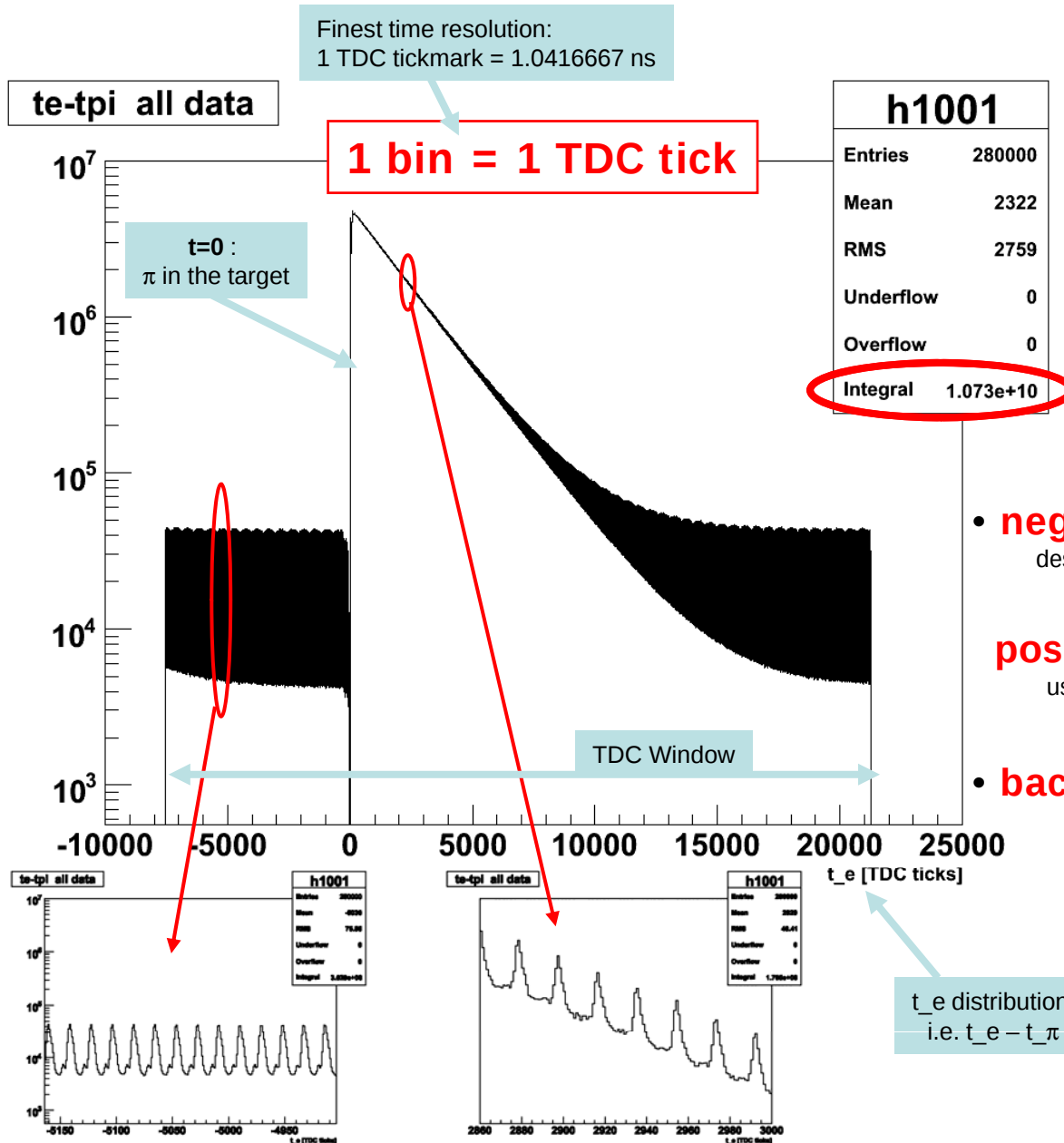
Example of a **REAL EVENT** (from online monitoring tool)



~10¹⁰ EVENTS LIKE THESE HAVE BEEN COLLECTED !!!



ANALYSIS OUTPUT: LIFETIME DISTRIBUTION



"THE" PLOT !!!

- t_e distribution i.e. $t_e - t_\pi$
- total stat : 10^{10} μ decay events

- **negative times** (pure bkg events) & description of the background (totally decoupled from the signal) from the negative times region

- **positive times** (signal+bkg)
use the background description also for the positive times region

- **background**: flat component
no time dependent

+ RF periodicity structure (T_{RF})
beam induced background

STRATEGY for MUON LIFETIME MEASUREMENT

τ_μ measurement = fit of the distribution

STEPS FOR THE FIT :

1. Study of the fine binning distribution

i.e. Study and understand all the structures in the data

→ RF structure

→ TDC non linearity ($t > 0$)

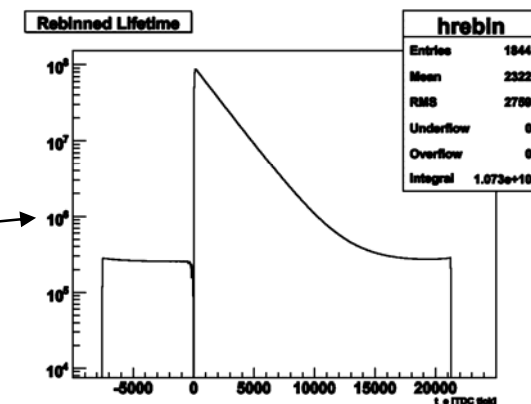
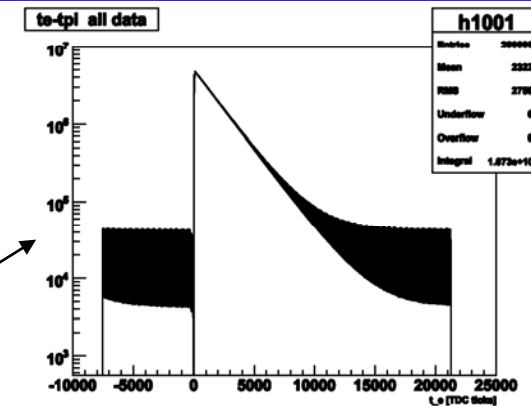
2. Rebin the histogram

(new bin size = T_{RF})

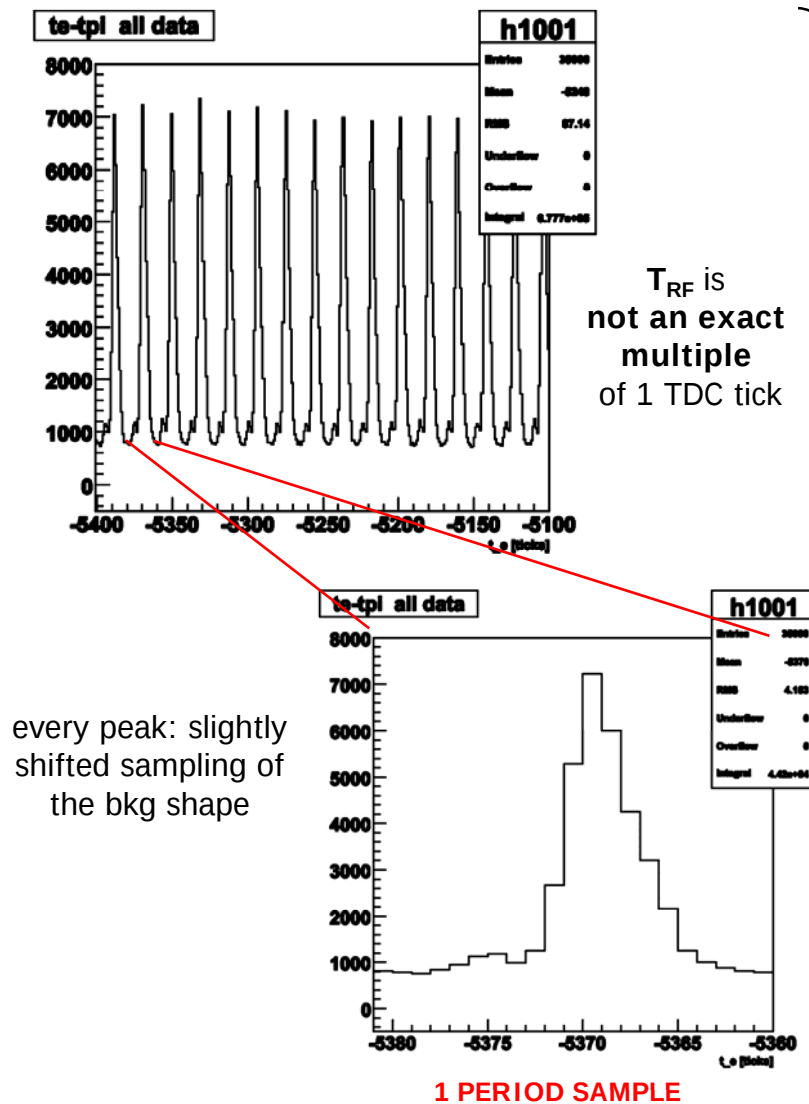
to minimize the effects of the periodic background on the lifetime measurement

3. Define a proper fitting function

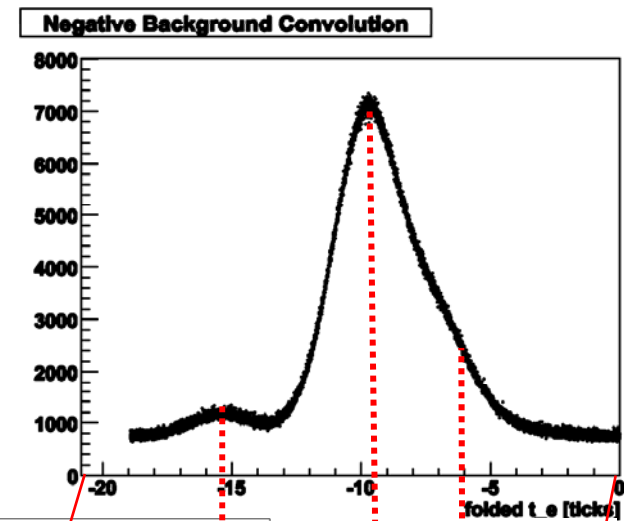
4. Binned maximum likelihood fit (TMinuit - ROOT) on the rebinned distribution, with τ_μ as free parameter



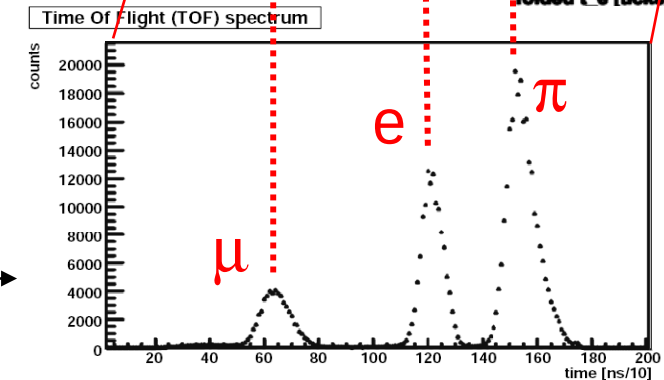
STEPS FOR THE FIT: understand the background ($t < 0$)



convolution
(T_{RF})



beam
TOF

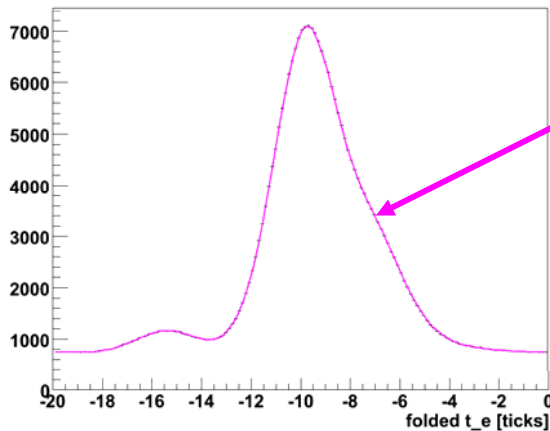


Periodic background shape:

- exactly reproduces the beam content
- dominated by e
- accurate description of the shape is possible (through a polynomial smooth interpolation)

STEPS FOR THE FIT: understand the background ($t < 0$)

Negative Background - Profile: Spline Interpolation



Polynomial (cubic) function defined on consecutive intervals limited by knots

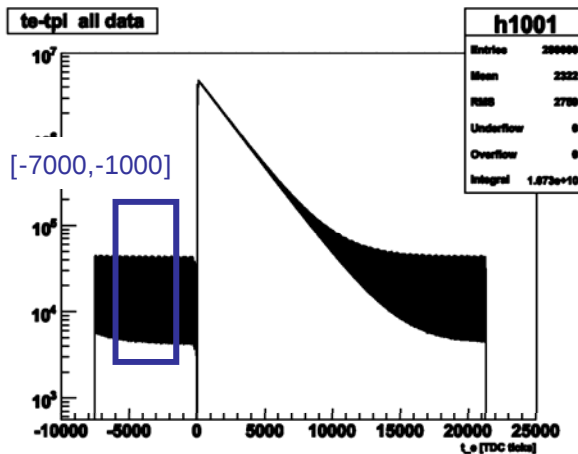
Spline interpolation (150 knots) of the bkg shape:
 $\rightarrow B(t)$

Periodic background description:

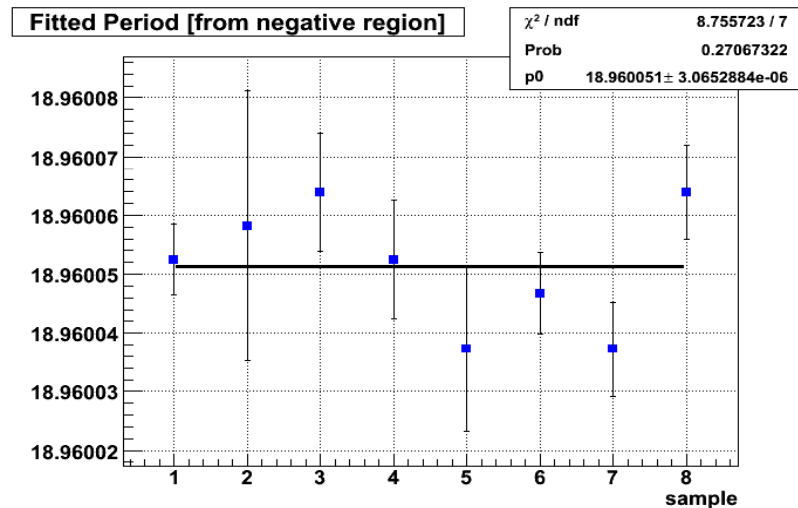
$$\rightarrow B(t_{rel}) \quad t_{rel} = \text{mod}(t - t_0, T_{RF})$$

Initial phase
 period

Negative times region fit
 (with fixed shape of the background)



T_{RF} free param
 in the fit



$$\rightarrow T_{RF} = [18.960051 \pm 0.000003] \text{ ticks}$$

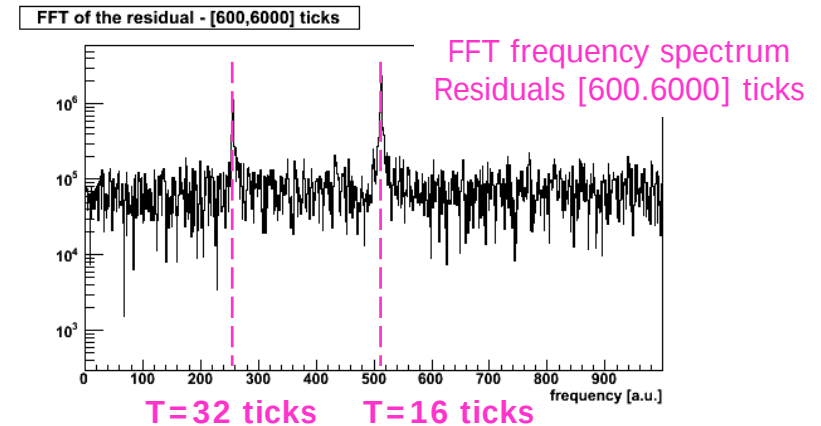
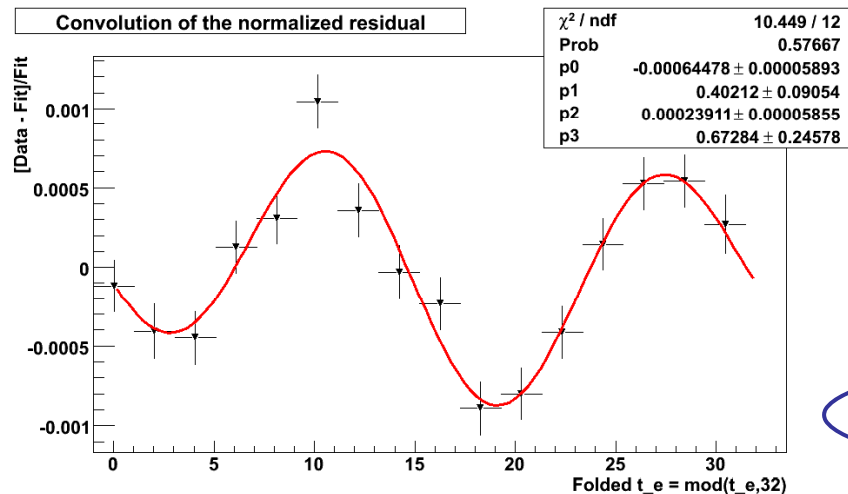
~ 0.2 ppm

$$N_{neg}(t) = B(t_{rel}) + P_{neg} + \frac{N_{neg}}{\tau} e^{-t/\tau}$$

STEPS FOR THE FIT: periodic structures in the data (t>0)

- Positive times region fit
- Fast Fourier Transform of its residual
- Convolution applied on the residual (T = 32)

mod(t,32)



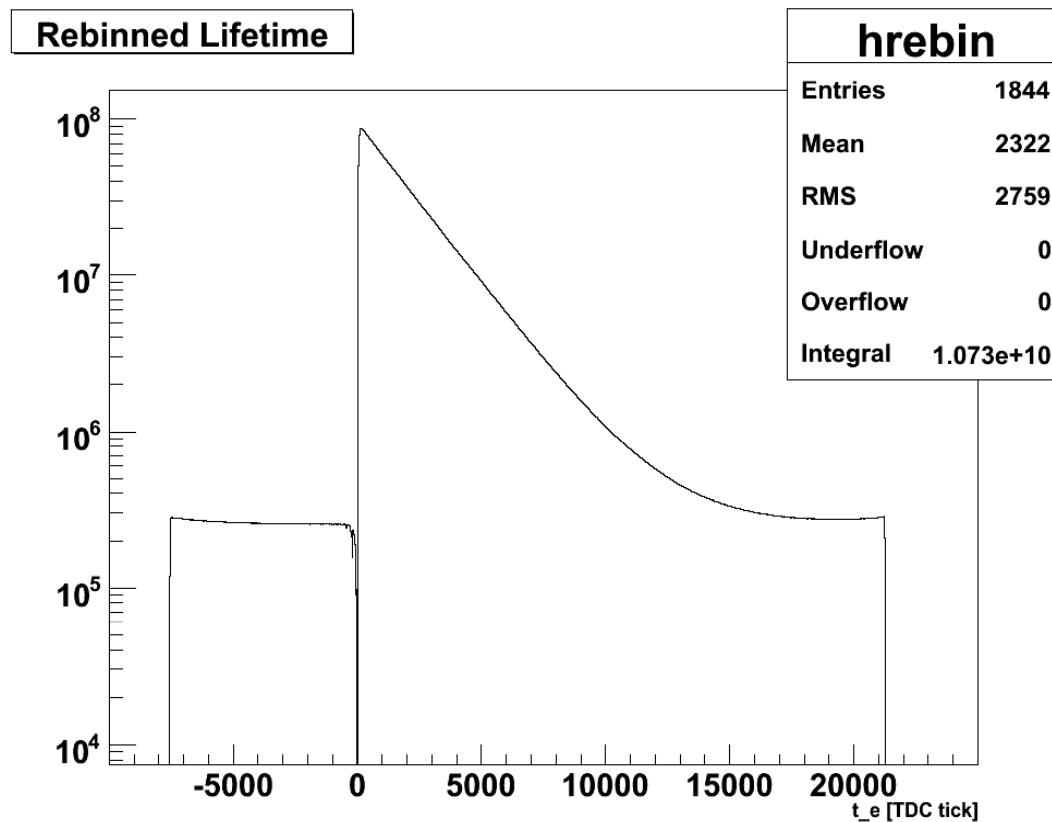
$$F_{tdc}(t) = p_1 \sin\left(\frac{2\pi t}{16} + p_2\right) + p_3 \sin\left(\frac{2\pi t}{32} + p_4\right)$$

Fitting function: $N(t) \longrightarrow [1 + F_{tdc}(t)] \times N(t)$

- TDC non linearity effects [TDC CLK = 32 ticks]
- per mille level effect
- confirmed also in lab tests

STEPS FOR THE FIT: rebin the histogram

- Rebin the histogram** using the measured beam period T_{RF}
- to minimize the influence of the periodic background on τ_μ measurement
 - information loss – but only on the details of the background, not the lifetime

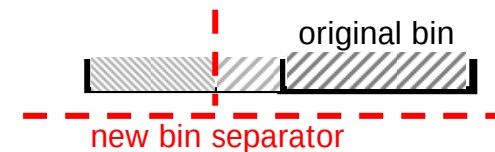


T_{RF}

1 new bin = 18.960051 original bins

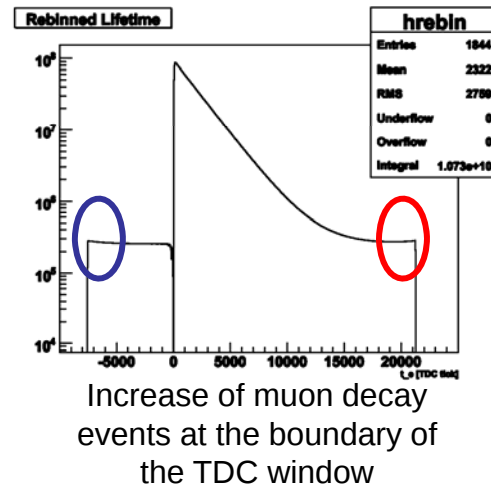
“SMART REBIN”

i. e. rebin + bin sharing procedure :

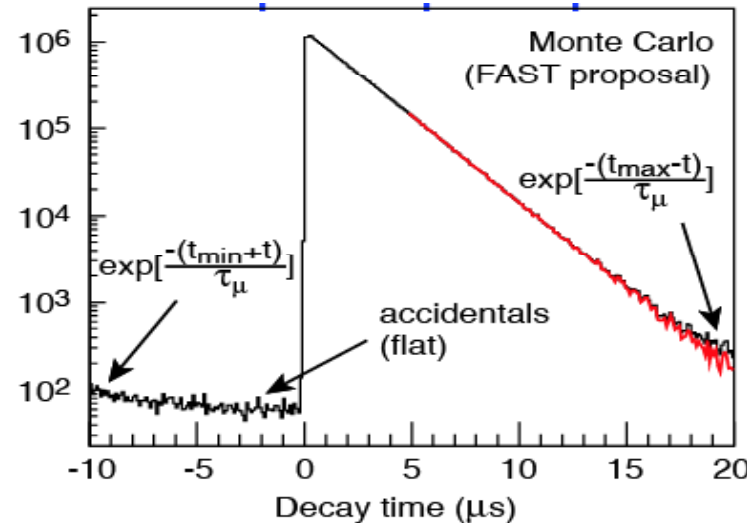


- different algorithms tried (uniform, linear, quadratic, exp) for the sharing of evts inside the original bin
- no appreciable differences found (see systematics)
- default: uniform distribution inside the bin

STEPS FOR THE FIT: boundary effects in the lifetime distr.



Already foreseen in the systematic study with MC simulations



Due to overlapping events in the TDC window $[t_{\min}, t_{\max}]$

$(\pi 1, \mu 1, e 1)$

$(\pi 2, \mu 2, e 2) \rightarrow (\pi 1, \mu 1, X)$

$(\pi 2, \mu 2, e 2)$

$X = \text{beam pcl} \rightarrow \text{beam induced bkg}$

$X = \pi 2 \rightarrow (\pi 1, \mu 1, \pi 2) \rightarrow \text{peaked at } t_{\max}$

$X = e 2 \rightarrow (\pi 1, \mu 1, e 2) \rightarrow \text{peaked at } t_{\min}$

$(\pi 1, \mu 1, \cancel{e 1}) (\pi 2, \mu 2, e 2)$

TDC time window

next window

$(\pi 2, \mu 2, e 2) (\pi 1, \mu 1, \cancel{e 1})$

previous window

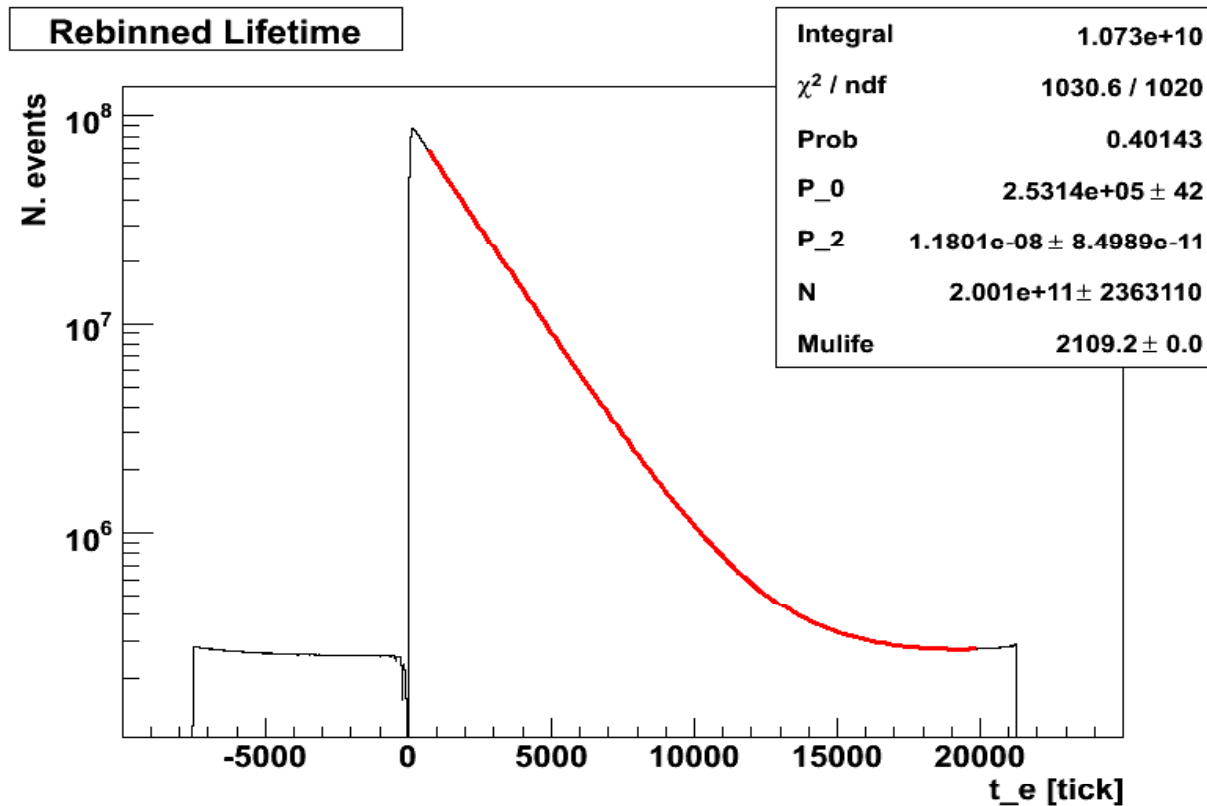
TDC time window

THE FIT

TDC non linearity Accidental bkg Signal Time dependent background

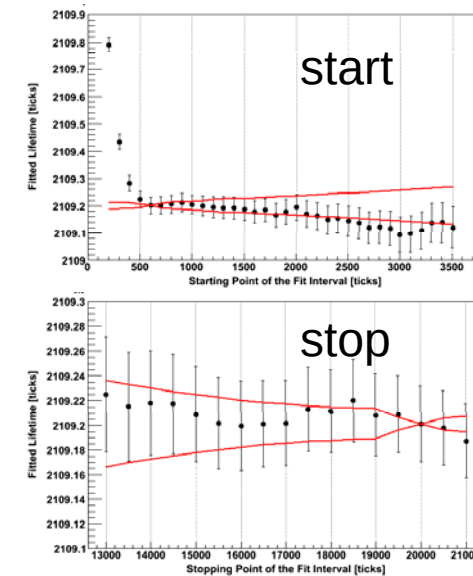
$$N(t) = [1 + F_{tdc}(t)] \times \left[P_0 + \frac{N_0}{\tau} (e^{-t/\tau} + P_2 e^{t/\tau}) \right]$$

no precise description of the periodic beam induced background is required



→ VERY HIGH QUALITY FIT

- Fit interval: **[600,20000]** ticks
Largest region of stable lifetime

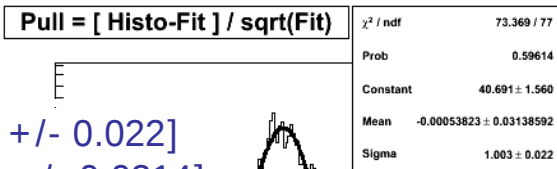
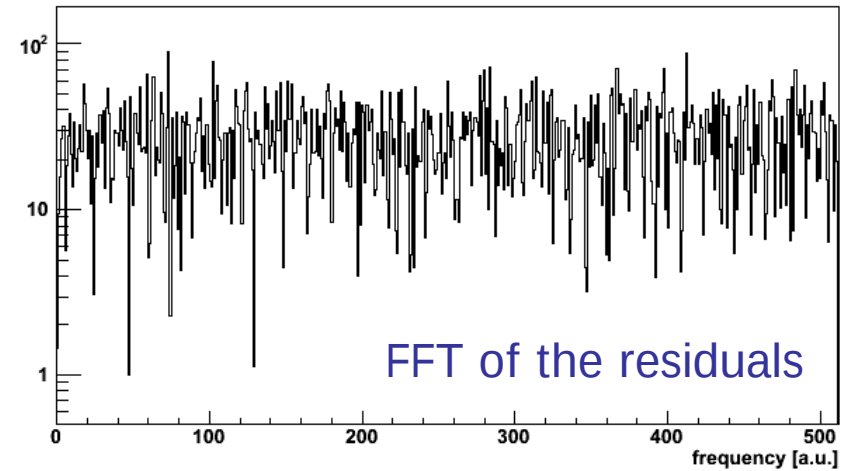


FIT QUALITY

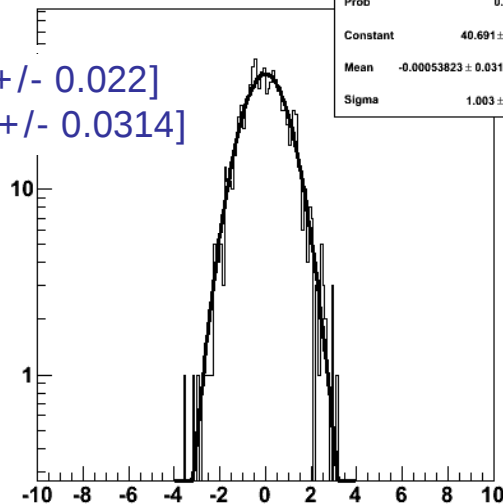
<i>Full Statistics Sample (Run2006)</i>		<i>Fit: [600, 20000] ticks</i>
<i>Smart Rebin Method</i>		
χ^2/ndf	1030.65/1020 = 1.0104	
Prob(χ^2 ,ndf)	0.4014	
Fitted Parameters		
Offset	P_0	253135 ± 39
Exp. Tail Norm.	P_2	$(1.180 \pm 0.008) \times 10^{-8}$
Normalization	N_0	$(2.00104 \pm 0.00002) \times 10^{11}$
Lifetime [ticks]	τ	2109.200 ± 0.031

	P_0	P_2	N_0	τ
P_0	1.000	-0.714	-0.104	-0.498
P_2	-0.714	1.000	0.084	0.335
N_0	-0.104	0.084	1.000	-0.157
τ	-0.498	0.335	-0.157	1.000

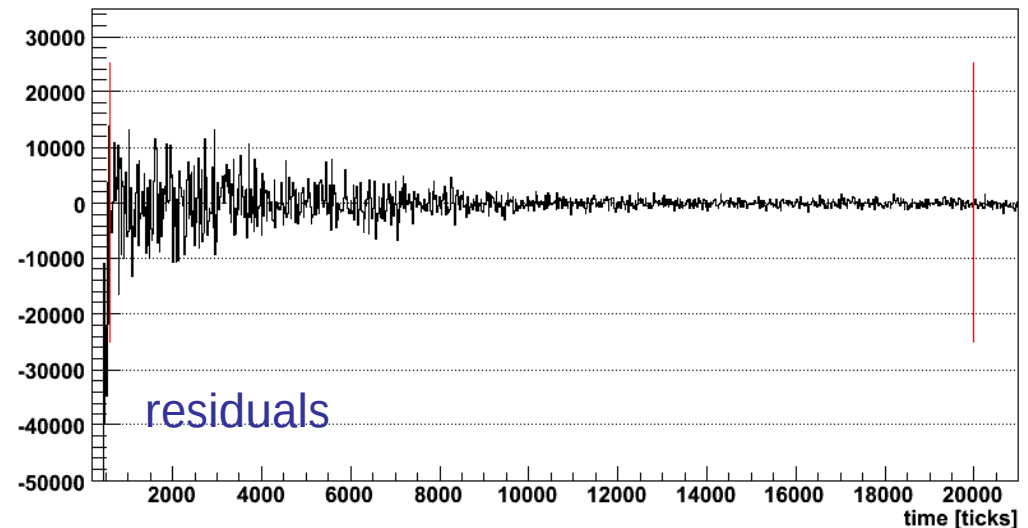
FFT of the residual - [600,20000] ticks



$\sigma = [1.003 \pm 0.022]$
 $X = [-0.0005 \pm 0.0314]$



histo - fit (full interval)



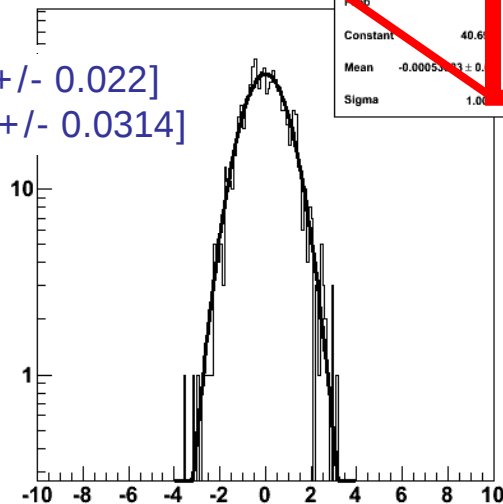
FIT QUALITY

Full Statistics Sample (Run2006)		Fit: [600,20000] ticks
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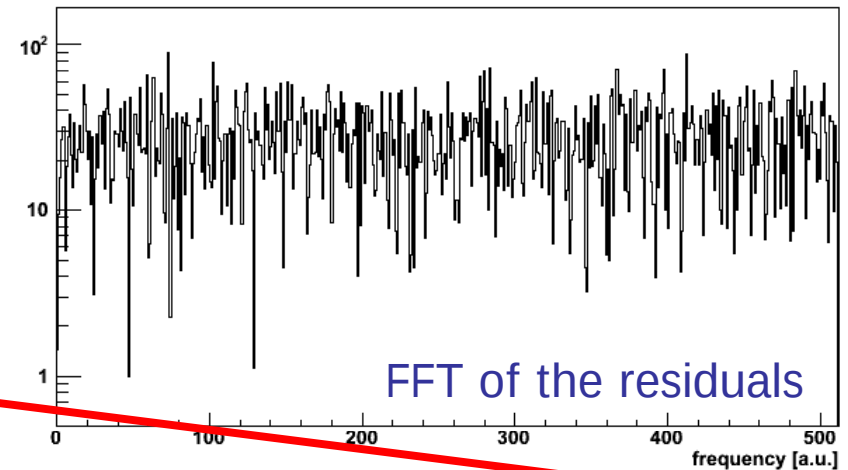
	P_0	P_2	N_0	τ
P_0	1.000	-0.714	-0.104	-0.498
P_2	-0.714	1.000	0.084	0.335
N_0	-0.104	0.084	1.000	-0.157
τ	-0.498	0.335	-0.157	1.000

Pull = [Histo-Fit] / sqrt(Fit)	χ^2/ndf	7
Constant	40.6	
Mean	-0.00053	13 ± 0.1
Sigma	1.00	

$\sigma = [1.003 \pm 0.022]$
 $\chi = [-0.0005 \pm 0.0314]$



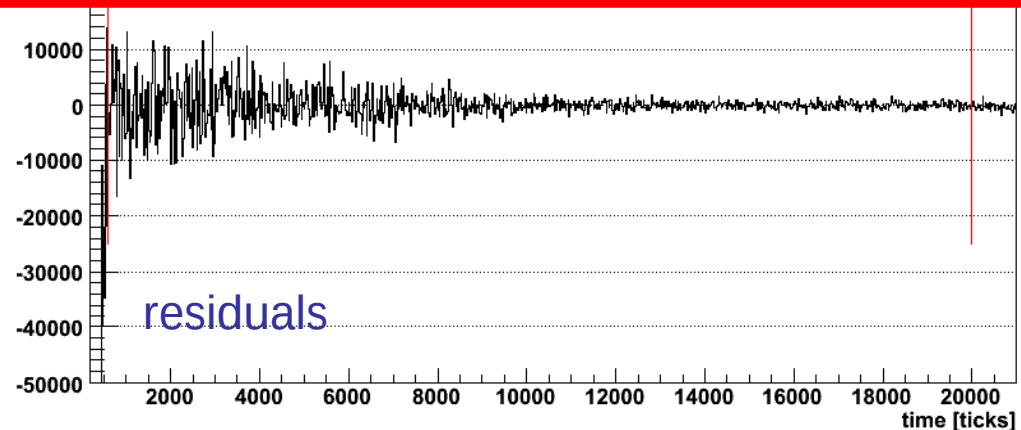
FFT of the residual - [600,20000] ticks



FFT of the residuals

$$\tau_\mu = [2197.083 \pm 0.032] \text{ ns}$$

$$\left(\frac{\delta \tau_\mu}{\tau_\mu} \right)_{\text{stat}} = 15 \text{ ppm}$$





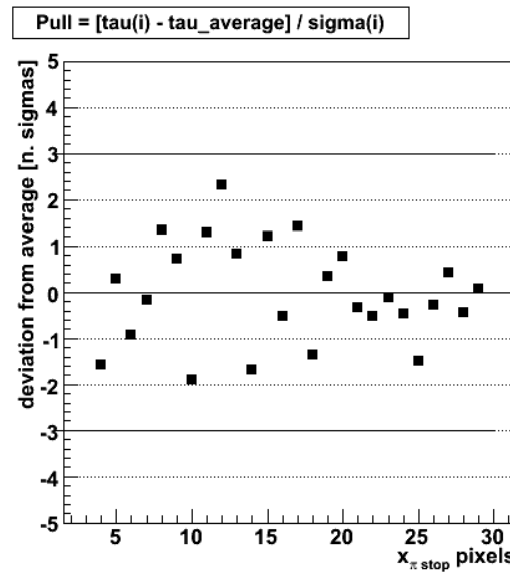
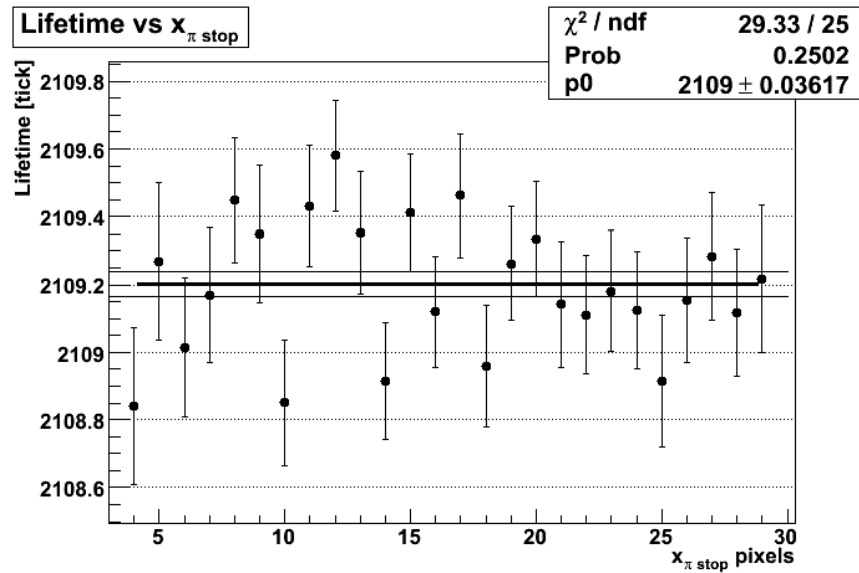
Systematic Uncertainty

SYSTEMATIC UNCERTAINTIES

- Different classes of systematic errors identified:
 - DETECTOR UNIFORMITY (τ_μ VS: x_π ; y_π ; position inside PSPM; PSPM; chip; TDC)
 - FIT METHOD
 - τ_μ ESTIMATOR ($t_e - t_\pi$ VS $t_e - t_\mu$)
 - μ SR EFFECTS
 - STABILITY OF THE MEASUREMENT (time stability, clock, rate dependence)
 - Evaluated using several dedicated histograms (produced online)
 - General recipe (when several lifetime measurements are available)
 - Any deviation inconsistent with the statistical fluctuations is considered to be of systematic origin
 - **A PRIORI consistency criteria = 3 sigma's**
 1. Fit histograms corresponding to the subsamples & compute the average
 2. Look if there are statistically incompatible points (i.e. deviation from the average $\Delta\tau_\mu > 3\sigma$)
 3. How much the average changes when those points are excluded
 4. Quote this variation as (signed) systematic shift
- 

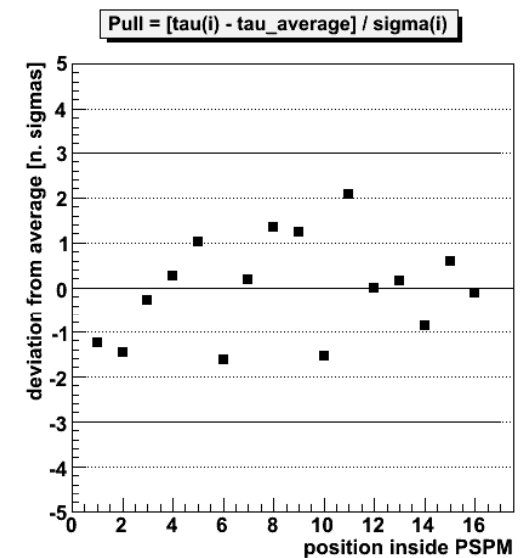
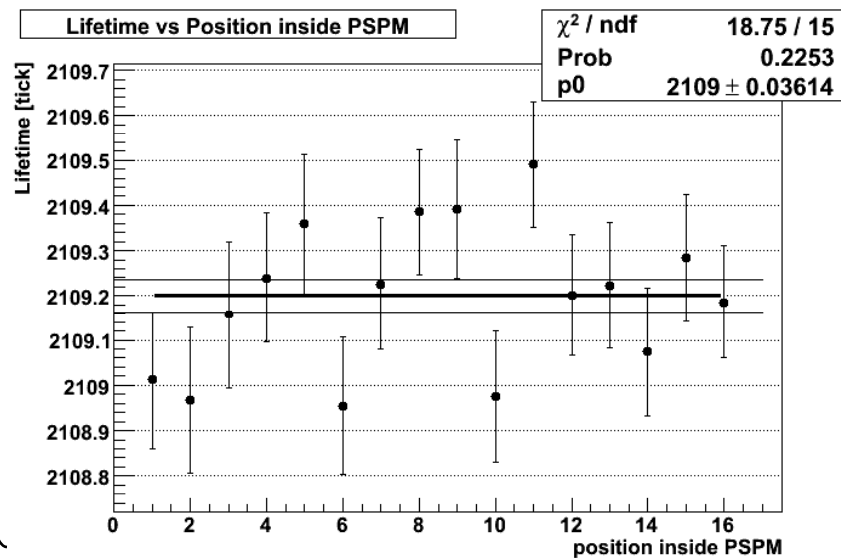
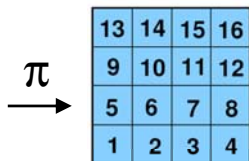
SYSTEMATICS: UNIFORMITY

2 examples for no evidence of a systematic effect beyond the expected statistical fluctuations



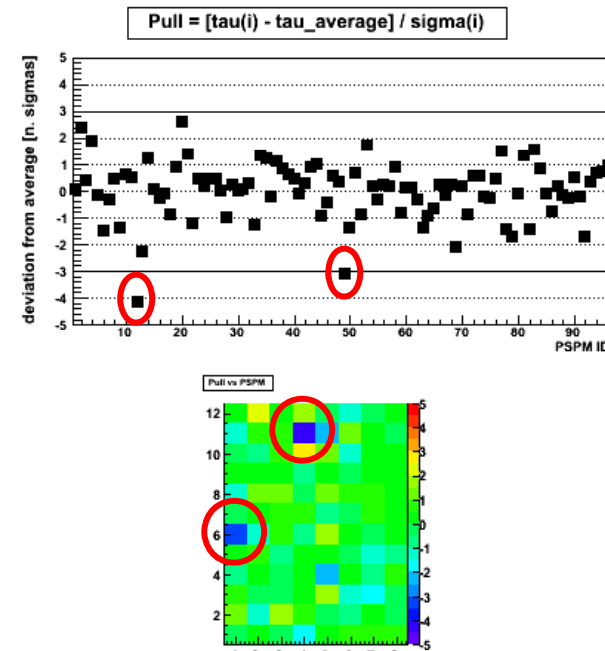
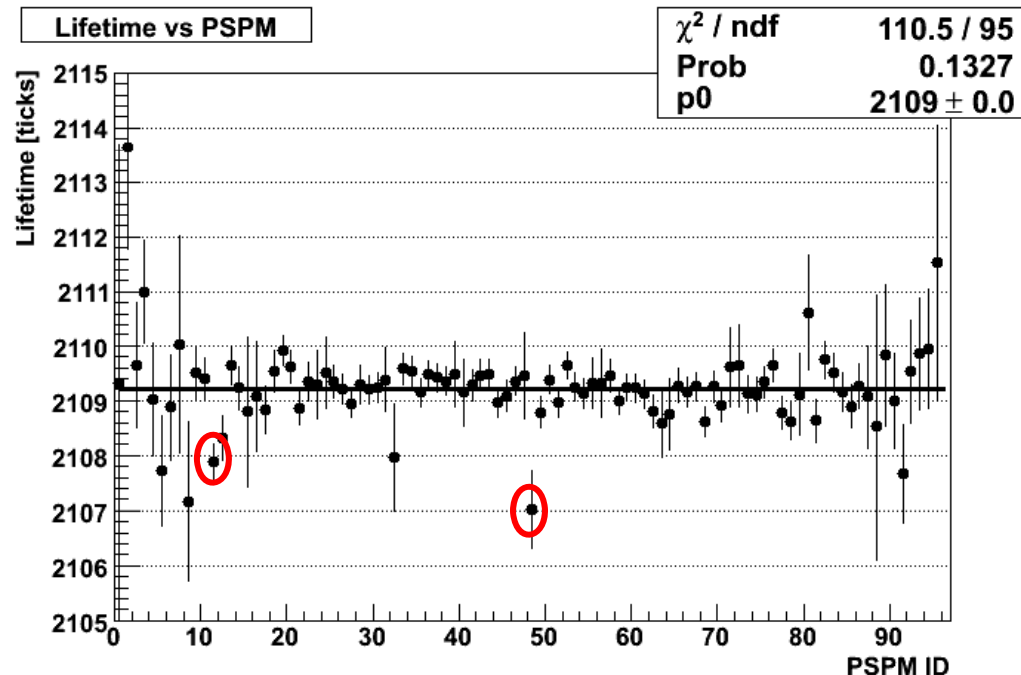
lifetime vs position
of the pion in the
target (x coord)

lifetime vs position
of the pion inside
the PSPM



SYSTEMATICS: UNIFORMITY

Lifetime VS position of the tube in the target:



• evidence for a systematic effect – due to 2 tubes

$$\Delta\tau_{\mu} = +0.016 \text{ ticks} = +7.6 \text{ ppm}$$

SYSTEMATICS -- GEOMETRY :

- lifetime vs pion position (x,y) ✓
- lifetime vs position inside the PSPM ✓
- lifetime vs detection efficiency ✓
- lifetime vs position of PSMP in the target ✗
- lifetime vs position of TDC chip in the target ✓
- lifetime vs position of TDC in the target ✓

Systematics associated to the target (dis)homogeneity

$$\Delta\tau_{\mu} = +0.016 \text{ ticks} = +7.6 \text{ ppm}$$

SYSTEMATICS: FIT METHOD

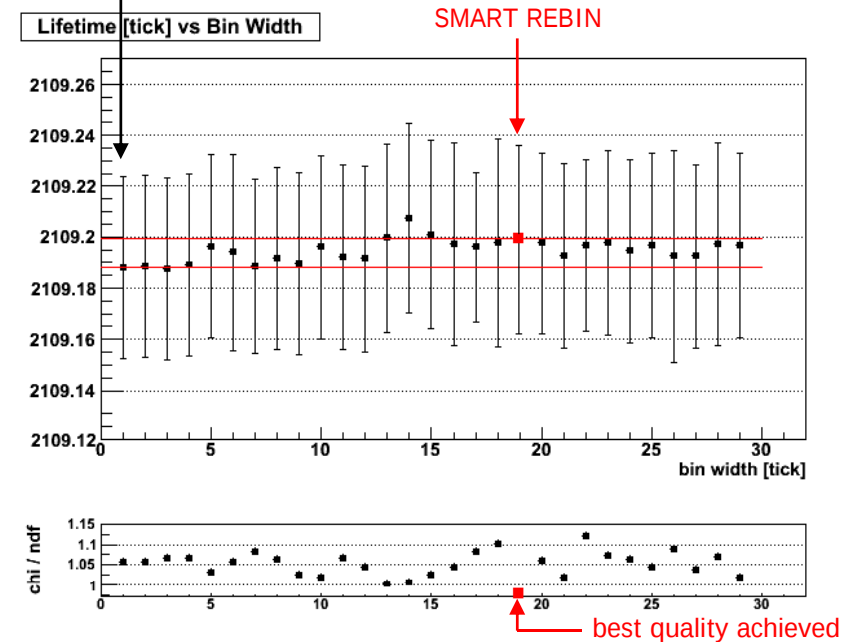
- smart rebin method VS fine binning fit
 - lifetime VS bin width
 - larger bin size = less required precision on the background description

Systematics associated to the fit method

$$\Delta\tau_\mu = -0.011 \text{ ticks} = -5.2 \text{ ppm}$$

Dominated by not satisfactory description of the background in the fine binning fit method

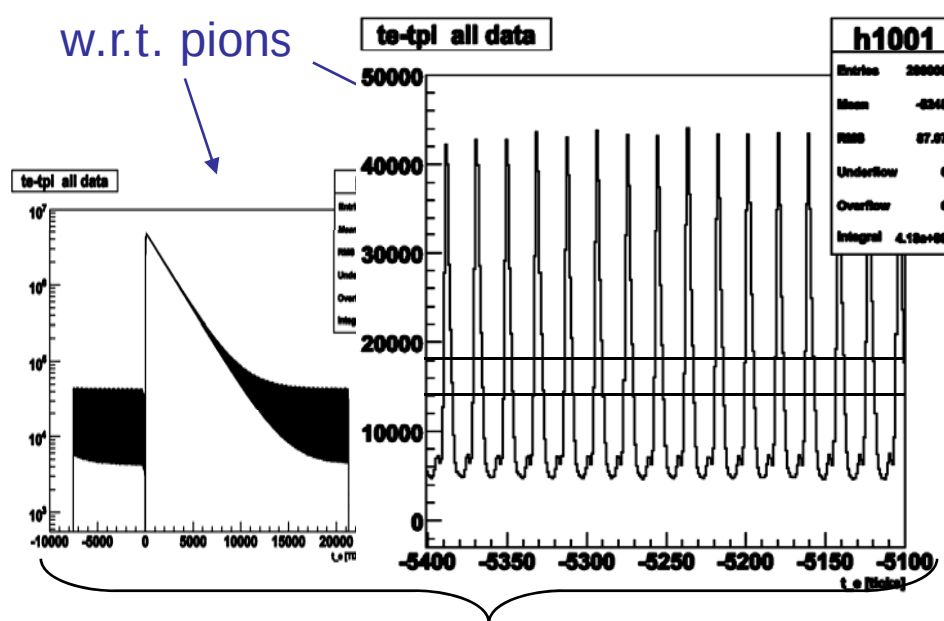
FINE BINNING FIT



CROSS CHECKS & VALIDATION OF THE REBIN METHOD

- exact value of T_{RF} $T_{RF} \pm 20 \sigma$'s $\Rightarrow \Delta\tau_\mu < 0.1 \text{ ppm}$
- phase of the periodic beam background t_0 in $[0, T_{RF}]$ $\Rightarrow \Delta\tau_\mu < 0.1 \text{ ppm}$
- different bin event migration algorithms (uniform, linear, quadratic) $\Rightarrow \Delta\tau_\mu < 0.1 \text{ ppm}$
- τ_μ VS number of integration steps $\Rightarrow \Delta\tau_\mu < 0.1 \text{ ppm}$

SYSTEMATICS: τ_μ ESTIMATOR

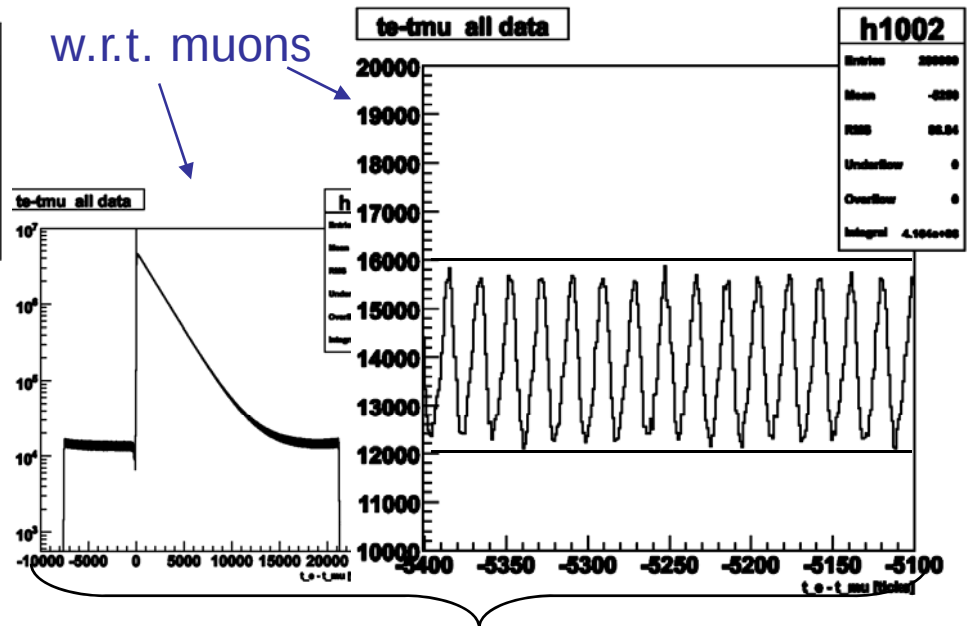


Nominal lifetime analysis: $t_e - t_\pi$

- independent on t_μ
- the analysis is focused on this

Systematics associated with the choice of the estimator

$$\Delta\tau_\mu = +0.0037 \text{ ticks} = +1.8 \text{ ppm.}$$



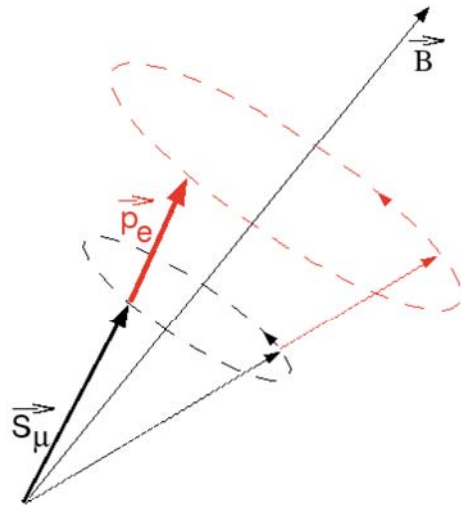
Alternative distribution: $t_e - t_\mu$

- less sensitive to the background shape
- larger uncertainty in the bkg description

- Estimator different from the one adopted for any other systematic study
- ➔ Independent lifetime measurement

SYSTEMATICS: μ SR EFFECTS

μ SR effects = effects on the lifetime of the $\vec{S}_\mu$ precession movement in a magnetic field



$$f_\mu = 13.55 \frac{\text{kHz}}{\text{G}} \times B \Rightarrow T_{\mu\text{SR}} \text{ precession period}$$

Why can this affect τ_μ ?

S_μ direction $\sim e^+$ direction (V-A structure of muon decay)

- *IF* polarized muons (i.e. preferential direction for S_μ)
 $\rightarrow$ time dependent angular distribution of e^+
- *IF* (in addition) anisotropies in the target
 $\rightarrow$ **time dependent detection efficiency** [time scale $T_{\mu\text{SR}}$]

2 remarks:

- **2nd order effect**, which requires both
 - Polarized μ 's**
 - Anisotropies in the target**
- but... ppm level precision!!
- unpolarized μ source: $\pi \rightarrow \mu$
 - beam μ 's suppression by range req.
 - uniformity ; large solid angle
 Both already strongly suppressed in the FAST design

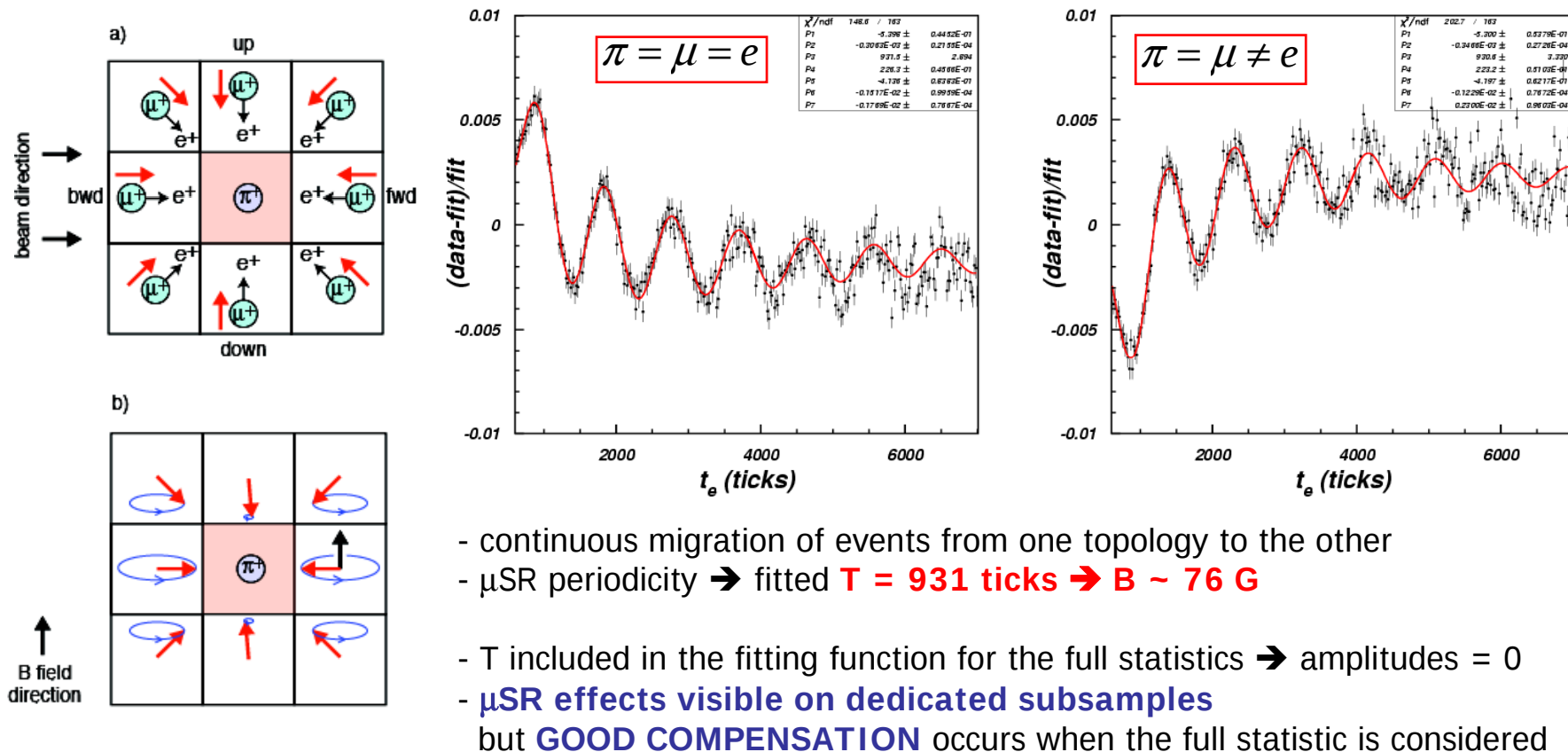
- **magnetic field & precession period** (τ_μ observation period $\sim 20 \mu\text{s}$)
 - $B \sim 0.5 \text{ G}$ (Hearth) $\rightarrow T_{\mu\text{SR}} \sim 150 \mu\text{s}$
 - $B \sim 80 \text{ G}$ (FAST magnet) $\rightarrow T_{\mu\text{SR}} \sim 0.9 \mu\text{s}$ $\leftarrow$ magnetic field to enhance the effects of μ SR on a **known and measurable** scale (RUNNING CONDITIONS 2006)

SYSTEMATICS: μ SR EFFECTS on lifetime measurement

- FFT Study $\Rightarrow$ no μ SR effects on the global τ_μ distribution

Systematics associated with μ SR:
negligible ($< 1\text{ppm}$)

- special subsamples of data $\rightarrow$ μ SR effects can be “explicitly forced to appear”



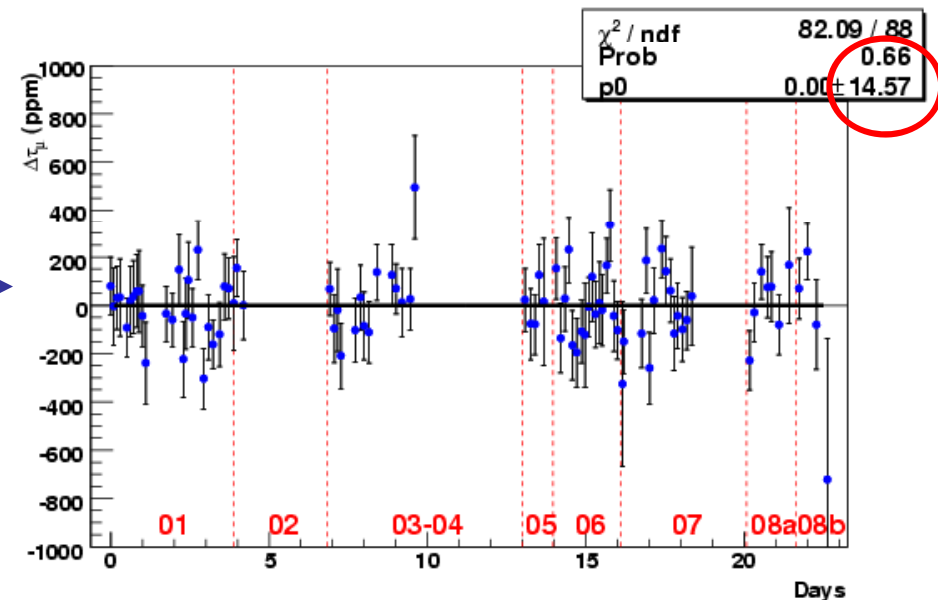
TIME STABILITY

Data set divided in 89 subsets of
similar size ($\sim 1.2 \cdot 10^8$ evts)
similar duration (~ 4 hours)

LIFETIME STABILITY

Nominal fit applied to every subset:

GOOD TIME STABILITY WITHIN STATISTICAL
UNCERTAINTY of **15 ppm**

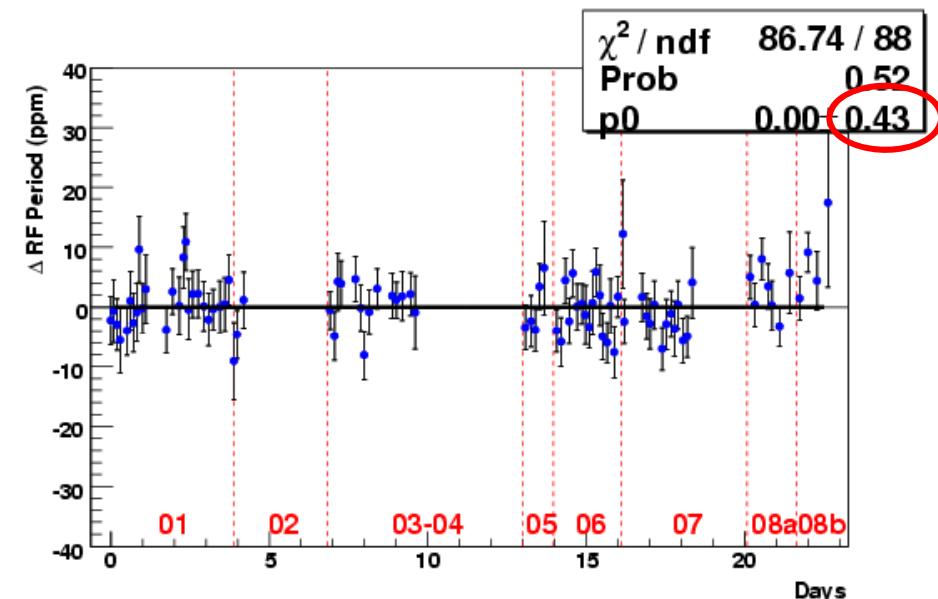


CLOCK STABILITY

Tested before & after data taking with
equivalent clock

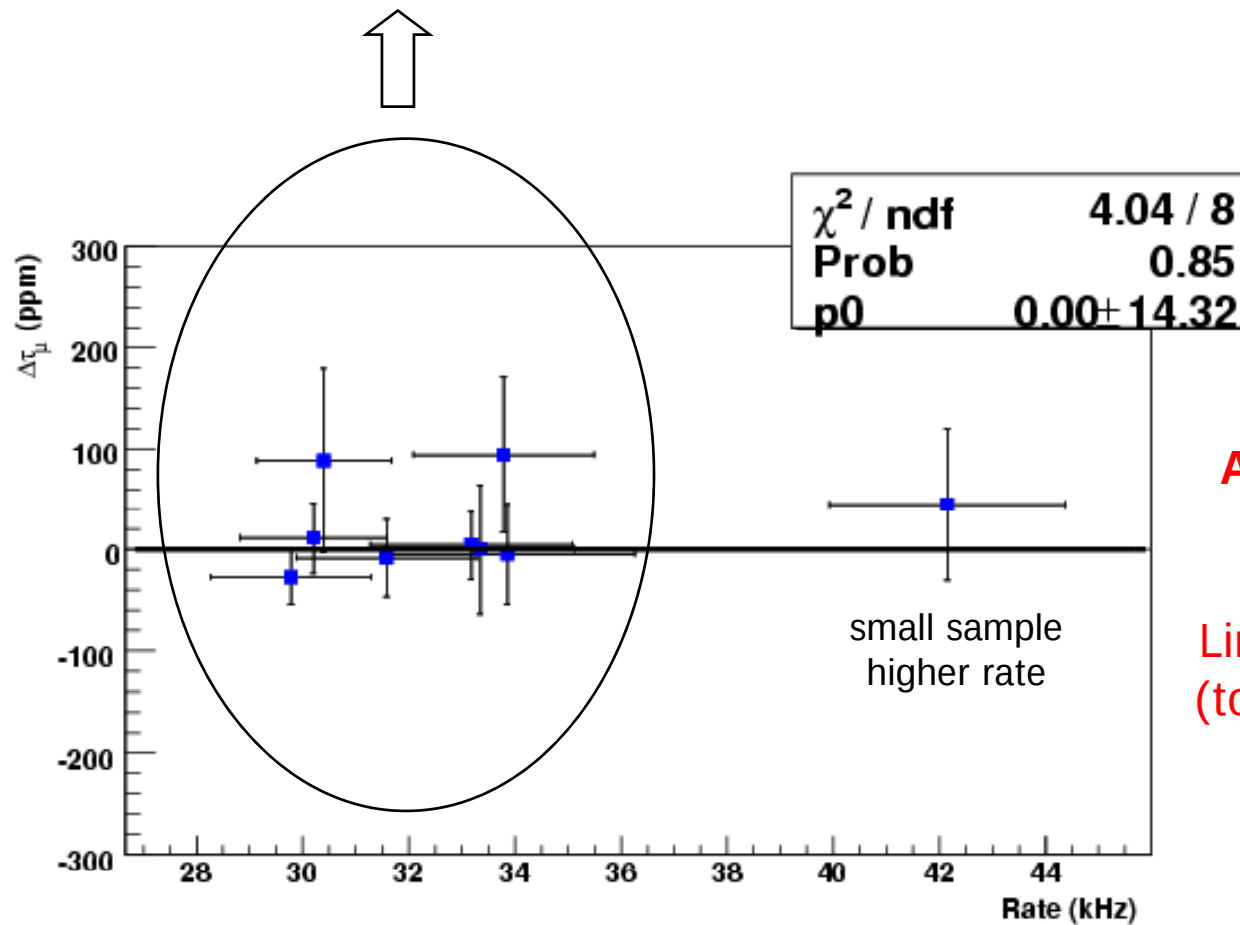
Tested **during data taking**: full Fourier transform
of negative times regions for every subset:

CLOCK IS STABLE WITHIN **0.5 ppm**



RATE DEPENDENCE

- Analyzed data sample
- Trigger rate (LV2) ~ 30 kHz
- Profit of the small spread in range to study lifetime VS rate



**Any effect of systematic
related to trigger rate**

**Limited rate interval available
(to be extended in the future)**

SYSTEMATIC UNCERTAINTIES: SUMMARY

SIGNED difference btw the 'alternative procedure' and the nominal fit
(i.e. Maximum bias allowed by our analysis method and our data sample)

Source of systematic	$\Delta\tau_\mu$ [ticks]	$\Delta\tau_\mu$ [ppm]
Homogeneity of the Target	+0.016	+7.6
Fit Method	-0.011	-5.2
Lifetime Estimator (i.e. $t_e - t_\mu$ vs $t_e - t_\pi$)	+0.004	+1.8
μ SR and Isotropy of the Target	-	< 1
Time Stability (i.e. clock)	-	< 1
Beam Rate	-	< 1
TDC performance (i.e. time smearing)	-	< 1
TOTAL	± 0.0137	± 6.5

- **no evidence for large systematic uncertainty in our data**
(within the statistical precision of the sample)
- **the determination of systematics is limited (and dominated) by the present statistics**
- **no correction to the central value from the nominal fit is applied**
SIGNED uncertainty quoted!
Conservative estimate of the systematics



**Conclusions:
Results (run 2006)
Present Status & Future Plans**

RESULTS (run2006)

- first precise measurement of the positive muon lifetime with the FAST experiment:

$$\tau_{\mu} = [2197.083 \pm 0.032 \text{ (stat)} \pm 0.015 \text{ (syst)}] \text{ ns}$$

- run 2006 [3 weeks data taking, Nov-Dec06]
- data sample : $1.073 \cdot 10^{10} \mu^+$ decay events
- precision comparable to PDG, value compatible with PDG
- uncertainty dominated by the statistics

$$\frac{\delta\tau_{\mu}}{\tau_{\mu}} = 16 \text{ ppm}$$

- FAST measurement of the Fermi coupling constant G_F

$$G_F = [1.166353 \pm 0.000009] \times 10^{-5} \text{ GeV}^{-2}$$

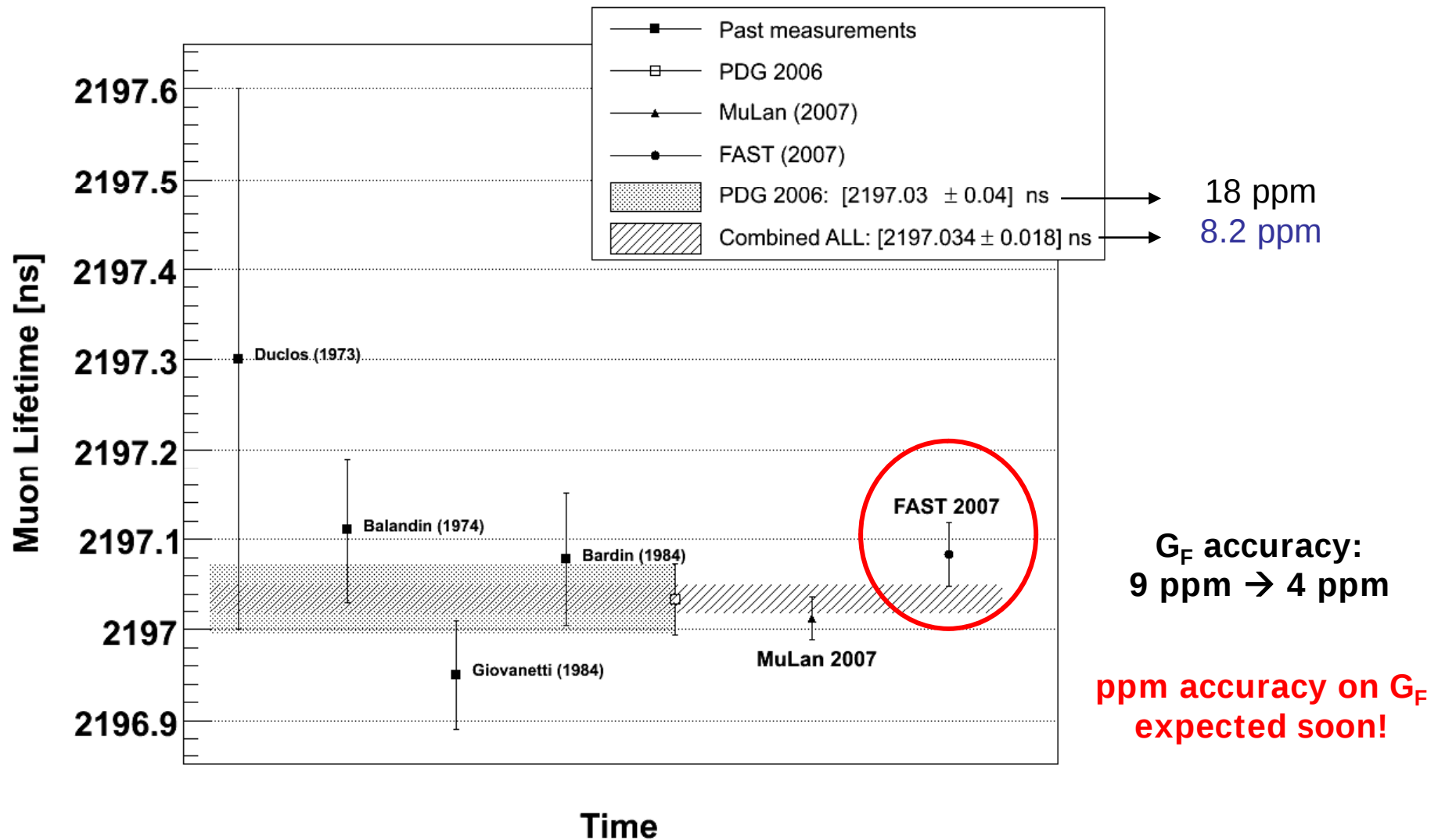
$$\frac{\delta G_F}{G_F} = 8 \text{ ppm}$$

**arXiv: 0707.3904 [hep-ex]
(July 2007)
&
submitted to PLB**

RESULTS

OUR MEASUREMENT IN THE WORLD SCENARIO OF MUON LIFETIME EXPERIMENTS

→ after more than 20 years two new experiments (MuLan & FAST) are taking the lead



FAST: PRESENT STATUS

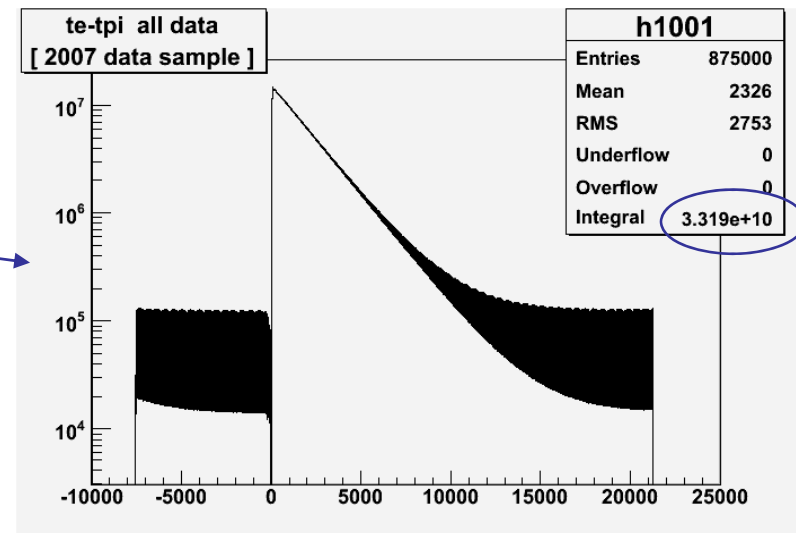
Run 2006 largely proved the feasibility of the experiment and the validity of the method for the measurement.

One main issue is still required to achieve the final goal [1ppm GF]

- **increase the working rate: 30 kHz LV2 (2006) → ~ 100 kHz LV2 (2007-2008)**

- 2007 beam time at PSI: Sept 2007 – Dec 2007

- not foreseen for physics data taking but **mainly devoted to DAQ / rate improvement**
- ~ 3×10^{10} muon decay events collected
[STILL **PRELIMINARY ANALYSIS**]



- **DAQ progresses:**

- Hardware : 4 PVIC nodes → 8 PVIC nodes i.e. **80 MB/sec → 160 MB/sec**
- 'malfunctioning' of the TDC induced by an anomaly in LV2 [**noise problem**]
[loss of synchronization among the 4 chips of the same TDC board]
→ partly solved => 60 kHz (stable running) accessible
- new mode of reading the TDCs: **continuous mode VS trigger matching mode**
- **100 kHz LV2 rate will be accessible using the TDCs in continuous mode**

FAST: FUTURE PLANS

- **2008 beam time** (to be defined, > May)
final data taking foreseen ; rate ~ 100 kHz (TDCs used in cont mode)
- to-do list :
 - complete the analysis for the sample collected in 2007 (~ 8ppm τ_μ)
 - develop new code for the event building with TDCs used in continuous mode
 - attempts to solve definitively the noise problem
 - higher statistical sample → new/unknown/unforeseen systematics

does not
require
beam time

requires
beam time

FINAL DATA COLLECTION FOR
FAST IS FORESEEN IN 2008

WORKS ARE STILL IN PROGRESS.....





